

Modelling and Simulation

In descending order of preference: (Alan Howling personal opinion!)

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1) ANALYTIC SOLUTION:

- gives physical understanding. Understand the ideal case before simulations.
- gives explicit scaling dependence of physical parameters.
- only applicable to simple cases, and simple cases often correspond to uniform situation. But if not uniform, then less interesting for applications!
- try to make each parameter separately uniform (e/m , composition, flow etc) for robust processing conditions and a wide operation window. Avoid empirical compensation of combinations of non-uniform parameters!
- useful to benchmark numerical simulation for confirmation and confidence (a numerical solution, if it converges, gives an answer. But is it correct?)

2) NUMERICAL CALCULATION OF ANALYTIC SOLUTION (eg Matlab programme)

3) NUMERICAL SOLUTION OF EQUATIONS (eg FlexPDE partial differential equation solver)

4) NUMERICAL SIMULATION (eg Siglo-RF; and COMSOL Multiphysics finite elements)

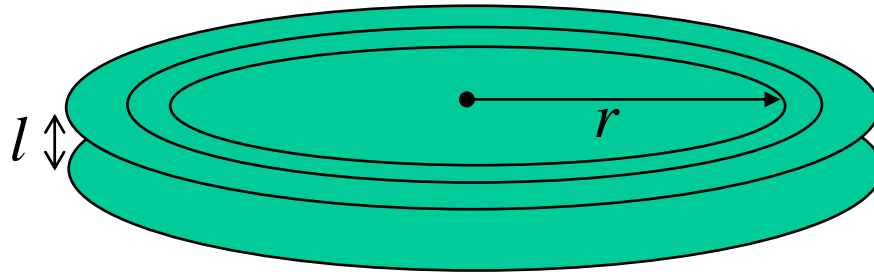
aah 1

Industry prefers full 3D plasma + many chemical reactions in their CAD design. Good luck!

1) ANALYTIC SOLUTION EXAMPLES

- cylindrical reactor standing wave for parallel plates
- cylindrical reactor standing wave correction with lens electrode
- showerhead 1D gas flow
- 0D plasma chemistry, depletion and microcrystallinity.
- time-resolved, equilibration time, dispersive axial flow
- wavefield solutions

Admittance of cylindrical parallel plates, gap l



Capacitance of parallel plates, $C = \frac{\epsilon_0 A}{l}$

Elemental cylindrical capacitance, $dC = \frac{\epsilon_0 2\pi r dr}{l}$

Capacitance per unit length in cylinder along $r = \frac{\epsilon_0 2\pi r}{l}$

Capacitive impedance $= \frac{1}{j\omega C}$, admittance $= j\omega C$.

Admittance per unit length of cylindrical parallel plates, $Y = j\omega \frac{\epsilon_0 2\pi r}{l}$

Effective permittivity of plasma-&-sheaths



Plasma short-circuits the transverse electric field:

$$\text{Combined capacitance of sheaths} = \frac{\epsilon_0 A}{2s},$$

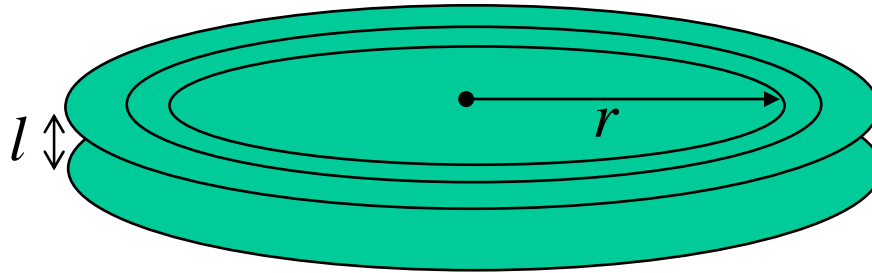
$$\text{Effective capacitance of the gap} = \frac{\epsilon_0 \epsilon_{\text{eff}} A}{l},$$

$$\therefore \text{Effective permittivity of the gap, } \epsilon_{\text{eff}} = \frac{l}{2s}. \quad (\epsilon_{\text{eff}} = 1 \text{ sans plasma; since } 2s = l)$$

Effective admittance per unit length of plasma-&-sheaths

$$\text{in cylindrical parallel plates, } Y = j\omega\epsilon_0\epsilon_{\text{eff}} \frac{2\pi r}{l}.$$

Series impedance of cylindrical parallel plates, gap l

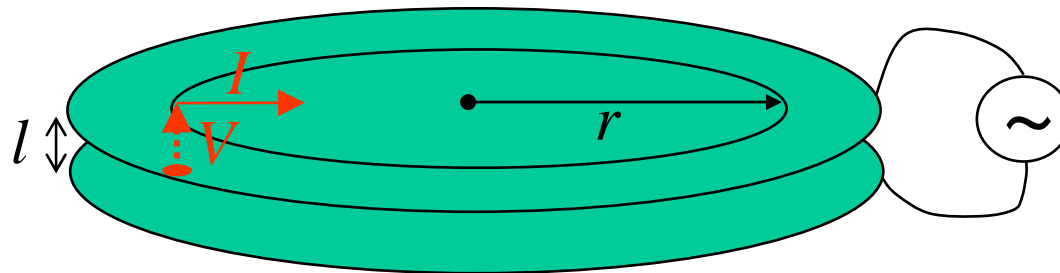


Inductance of cylindrical element, $dL = \frac{\mu_0 l dr}{2\pi r}$,

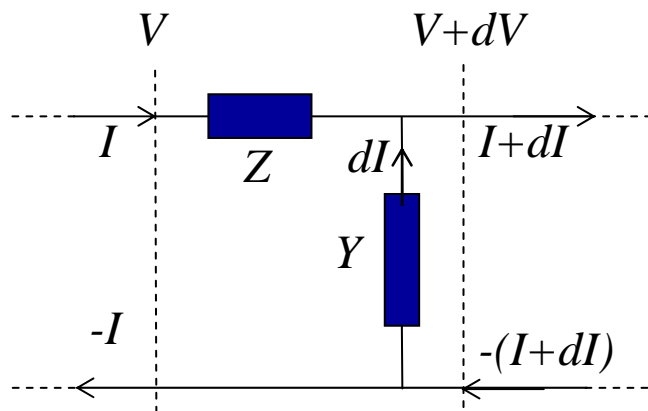
Impedance of cylindrical element $= j\omega \frac{\mu_0 l dr}{2\pi r}$.

Series impedance in cylinder per unit length along r , is $Z = j\omega\mu_0 \frac{l}{2\pi r}$.

Consider a *general* cylindrical transmission line



Uniform voltage and current around the circumference, open circuit on axis, series impedance Z , and parallel admittance Y , per unit length along r .



Kirchoff's laws: $\frac{dV}{dr} = -IZ$, $\frac{dI}{dr} = -YV$.

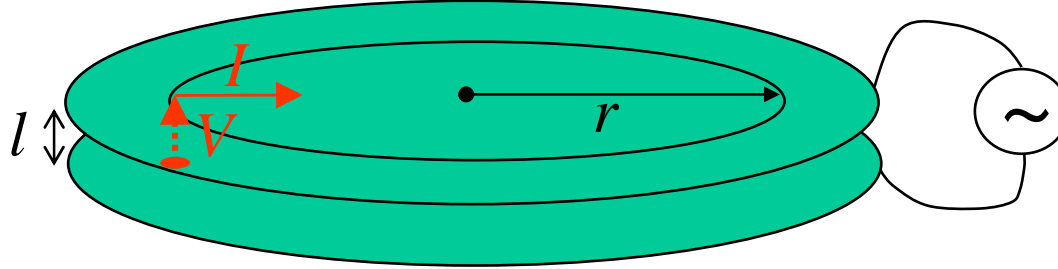
Substitute for I (or for V):

$$\frac{d^2V}{dr^2} = \left(\frac{1}{Z} \frac{dZ}{dr} \right) \frac{dV}{dr} + YZV, \text{ which is the}$$

general voltage wave equation for a cylindrical transmission line.

Consider a *parallel-plate* cylindrical transmission line

l is constant,
 V is variable.



Use the parallel-plate expressions: $Z = j\omega\mu_0 \frac{l}{2\pi r}$, $Y = j\omega\epsilon_0\epsilon_{\text{eff}} \frac{2\pi r}{l}$

$\therefore \left(\frac{1}{Z} \frac{dZ}{dr} \right) = -\frac{1}{r}$ and the general cylindrical transmission line equation is:

$\frac{d^2V}{dr^2} + \frac{1}{r} \frac{dV}{dr} + k^2V = 0$, which is the voltage wave equation which gives a

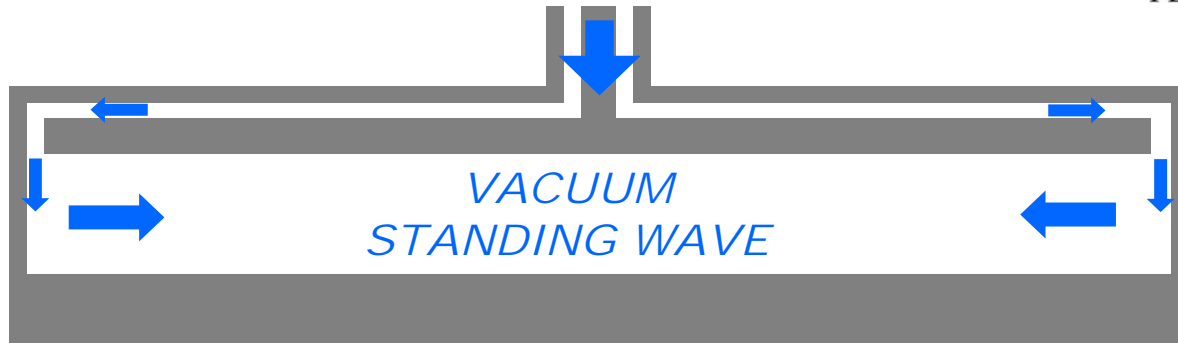
zero-order Bessel function solution for parallel-plate cylindrical geometry,

where $k^2 = -YZ = \omega^2\mu_0\epsilon_0\epsilon_{\text{eff}} = k_0^2\epsilon_{\text{eff}}$;

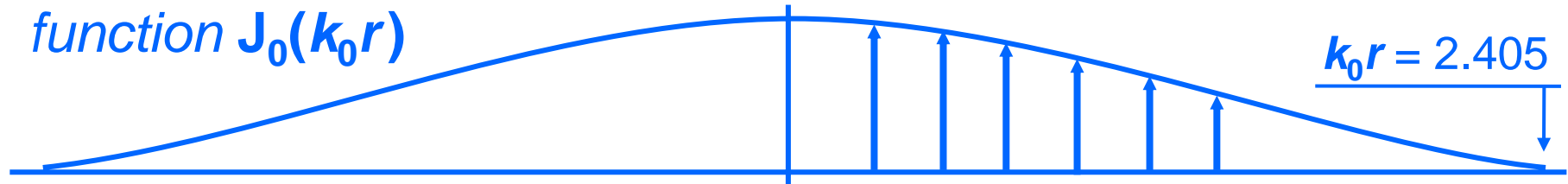
i.e. $k = k_0\epsilon_{\text{eff}}$, and the wave phase velocity $= \frac{1}{\sqrt{\mu_0\epsilon_0\epsilon_{\text{eff}}}} = \frac{c}{\sqrt{\epsilon_{\text{eff}}}}$.

(sheath width s & ϵ_{eff} have been assumed independent of V)

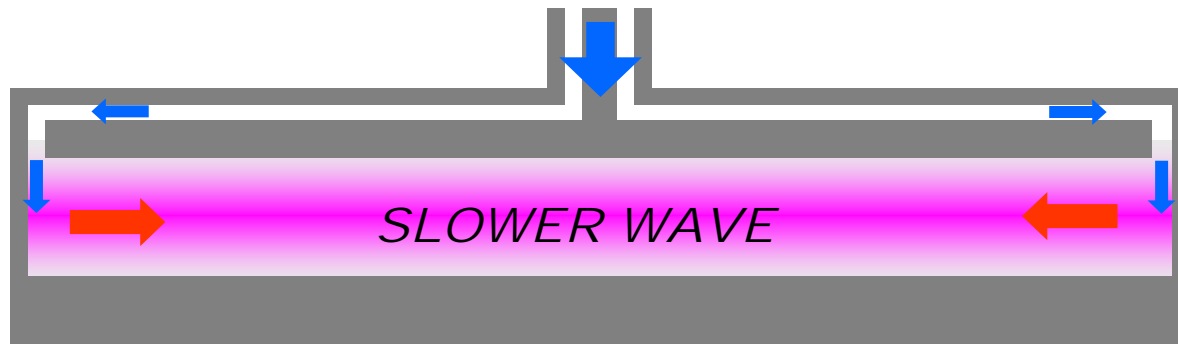
Bessel function standing waves, parallel plates



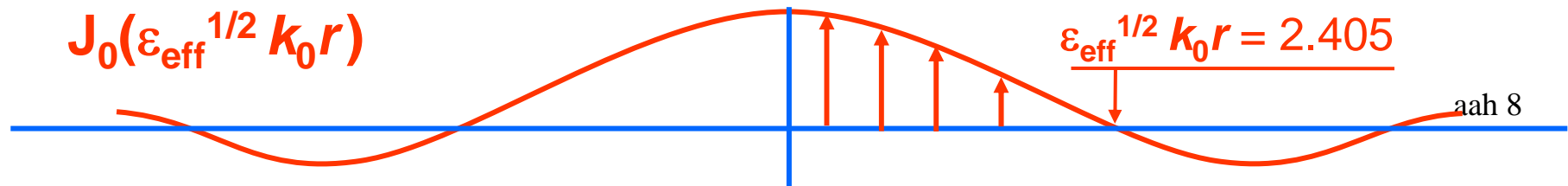
Bessel
function $J_0(k_0 r)$



ϵ_{eff} "plasma equivalent dielectric" acts as a worsening factor for uniformity:



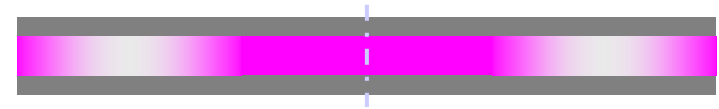
$J_0(\epsilon_{\text{eff}}^{1/2} k_0 r)$



Bessel function standing waves, parallel plates at 100 MHz

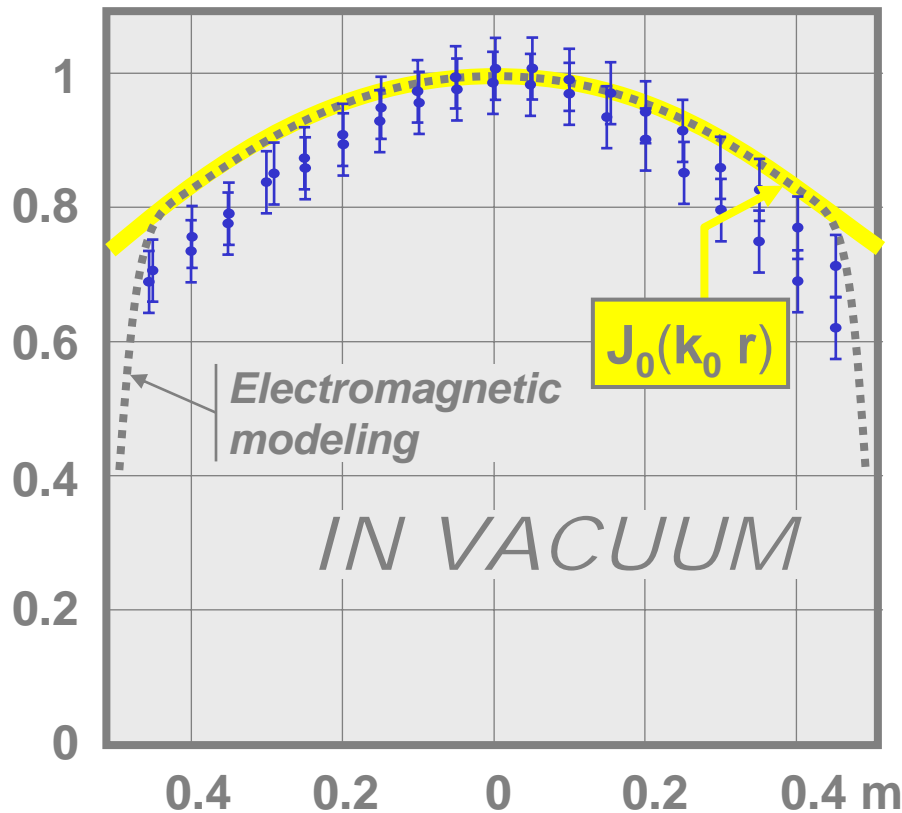
J. Appl. Phys. **95** 4559 (2004)

worsening factor with plasma means
that the first node falls inside the reactor!

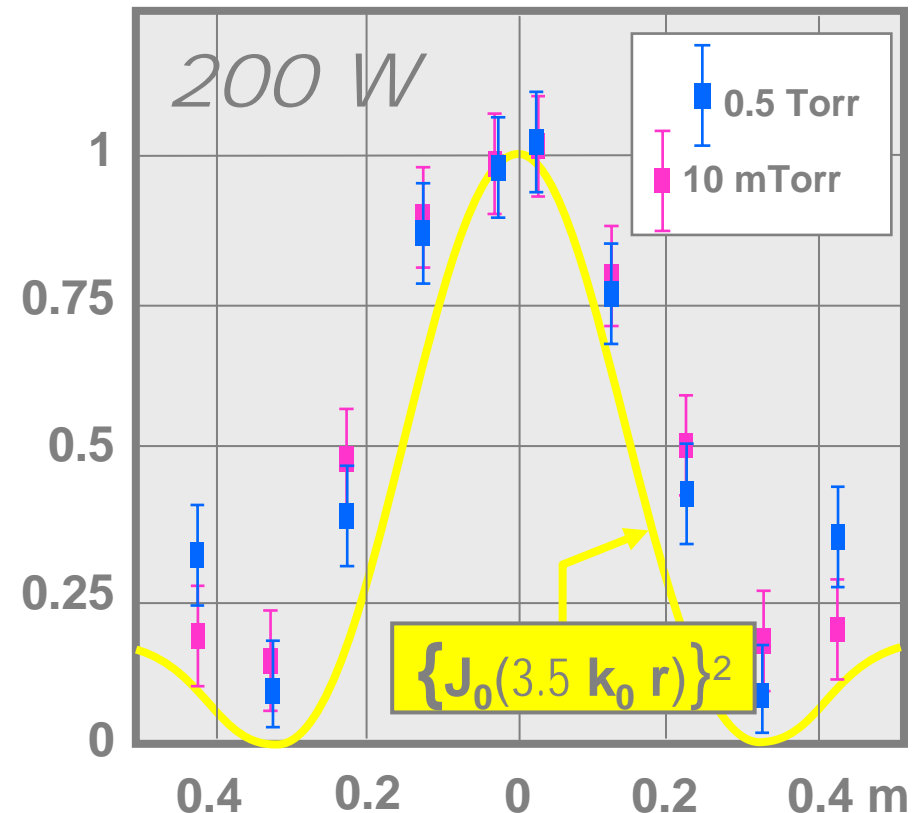


E-field

probe array ion saturation currents



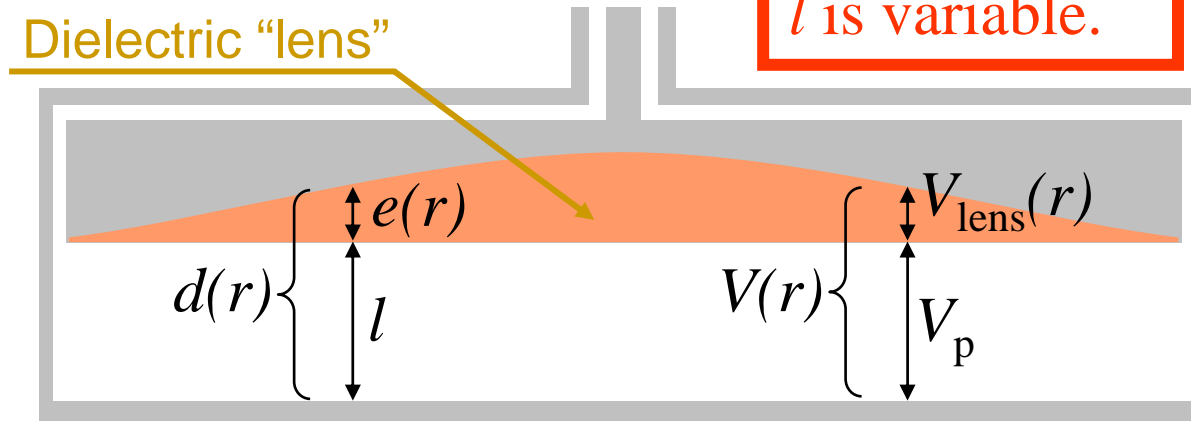
1 metre



1 metre

World's Simplest Lens Solution

adapted from: P. Chabert *et al*, Phys. Pl. 11, 4081 (2004).

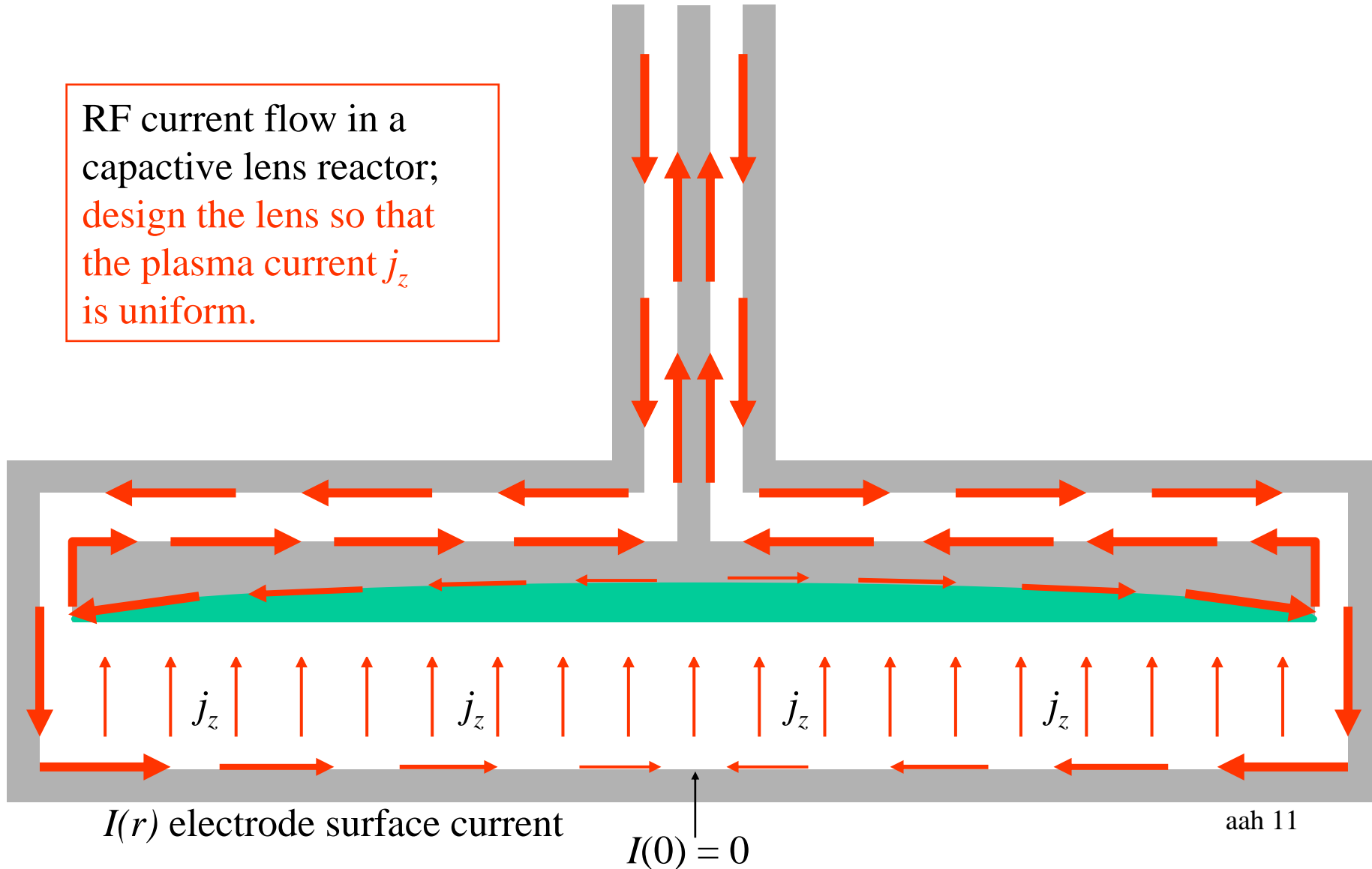


We keep a constant plasma gap, l ,
but add a variable thickness lens $e(r)$.
Total electrode gap is now $d(r) = l + e(r)$.

The plasma voltage is V_p , which we *define* constant,
the voltage across the lens thickness is $V_{\text{lens}}(r)$.
The total electrode voltage is $V(r) = V_p + V_{\text{lens}}(r)$.

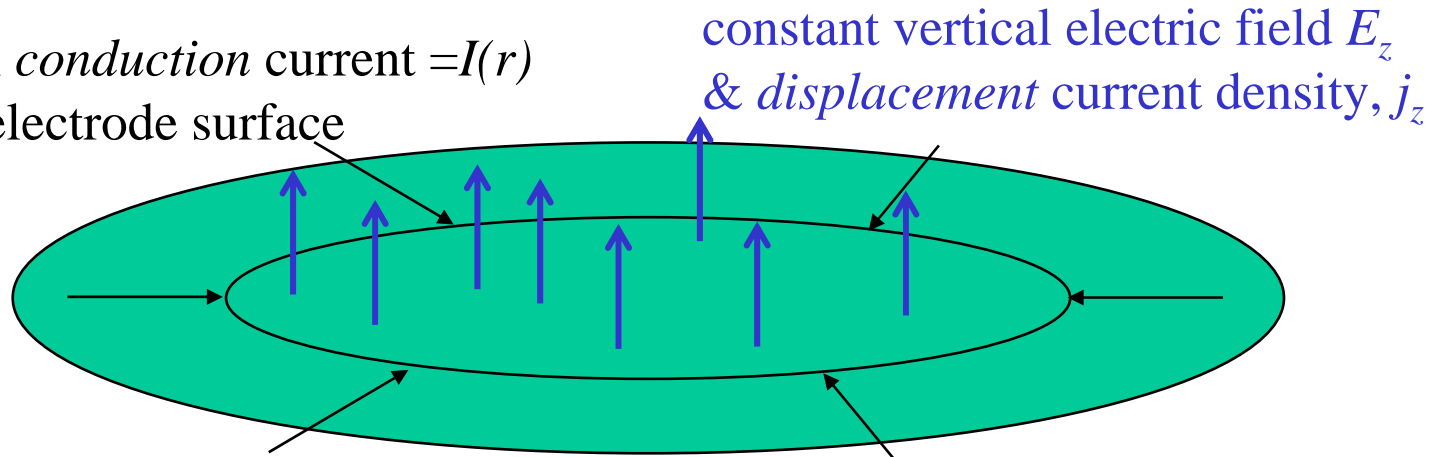
World's Simplest Lens Solution; introduction

RF current flow in a
capacitive lens reactor;
design the lens so that
the plasma current j_z
is uniform.



World's Simplest Lens Solution, I.

total radial *conduction* current $= I(r)$
along the electrode surface



1) We require a constant vertical electric field in gap, $E_z = \frac{V_p}{l} = \text{const.}$

2) \therefore require constant vertical current density $j_z = \frac{j\omega\epsilon_0\epsilon_{\text{eff}}V_p}{l} = \boxed{\frac{j\omega\epsilon_0\epsilon_r V_{\text{lens}}(r)}{e(r)}}$

3) The radial current in electrodes, $I(r) = -j_z\pi r^2$

(all the current entering radius r radially, must leave vertically,

because $I(0) = 0$, and $j_z = \text{constant over all } r$.)

World's Simplest Lens Solution, II.

4) To calculate $V(r)$, use Ohm's law radially: $dV(r) = -I(r)Z(r)dr$,

where $Z(r) = j\omega\mu_0 \frac{d(r)}{2\pi r}$ is the series impedance of the gap, per unit radius.

5) Substitute: $\frac{dV(r)}{dr} = j_z \pi r^2 Z = \frac{j\omega\epsilon_0\epsilon_r V_{\text{lens}}(r)}{e(r)} \pi r^2 \cdot j\omega\mu_0 \frac{d(r)}{2\pi r}$,

$\therefore \frac{dV_{\text{lens}}(r)}{dr} = -k_0^2 \epsilon_r V_{\text{lens}}(r) \frac{d(r)}{e(r)} \frac{r}{2}$, since $V(r) = V_{\text{lens}}(r) + V_p$.

6) Substitute for $V_{\text{lens}}(r)$ using 2): $V_{\text{lens}}(r) = \frac{\epsilon_{\text{eff}}}{\epsilon_r} \frac{V_p}{l} e(r)$ so that

$e'(r) = -k_0^2 \epsilon_r d(r) \frac{r}{2}$, and since $d(r) = e(r) + l$, $d'(r) = -k_0^2 \epsilon_r d(r) \frac{r}{2}$.

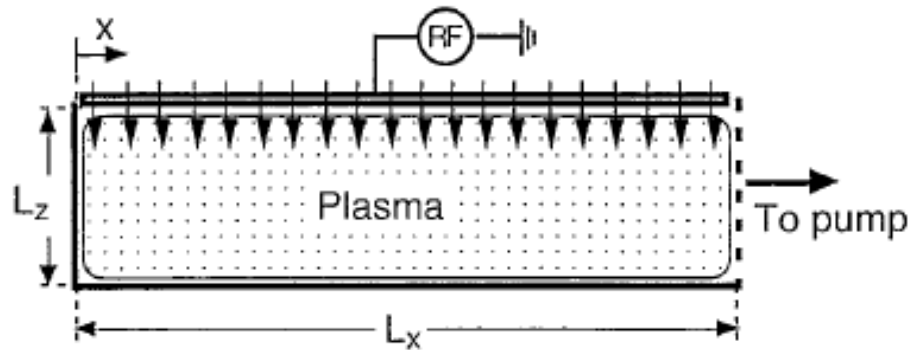
7) $\therefore d(r) = (l + e(0)) \exp\left(\frac{-k_0^2 \epsilon_r r^2}{4}\right)$, a Gaussian lens.

Lens shape depends on ϵ_r , not ϵ_{eff} . \therefore Lens shape independent of plasma.

A gas flow uniformity study in large-area showerhead reactors for RF plasma deposition

L Sansonnens, A A Howling and Ch Hollenstein

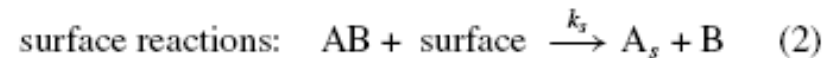
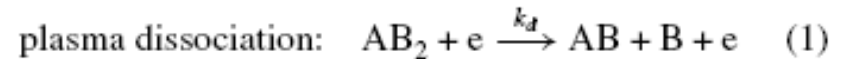
Plasma Sources Sci. Technol. 9 (2000) 205–209.



simple 1D model suggests that gas composition is spatially uniform across a showerhead reactor with a uniform plasma,

i.e. a 0D model can be justified for a large area showerhead reactor

basic plasma chemistry



species continuity equations

$$\frac{d}{dx}(n_{AB_2}v(x)) = D_{AB_2}\frac{d^2n_{AB_2}}{dx^2} + \phi - k_d n_e n_{AB_2} \quad (5)$$

$$\frac{d}{dx}(n_{AB}v(x)) = D_{AB}\frac{d^2n_{AB}}{dx^2} + k_d n_e n_{AB_2} - k_s n_{AB} \quad (6)$$

$$\frac{d}{dx}(n_B v(x)) = D_B \frac{d^2 n_B}{dx^2} + k_d n_e n_{AB_2} + k_s n_{AB} \quad (7)$$

$$n_t = n_{AB_2} + n_{AB} + n_B = \text{constant.}$$

unique solution

$$v(x) = ax \quad \text{and} \quad n_i = \text{constant } \forall i$$

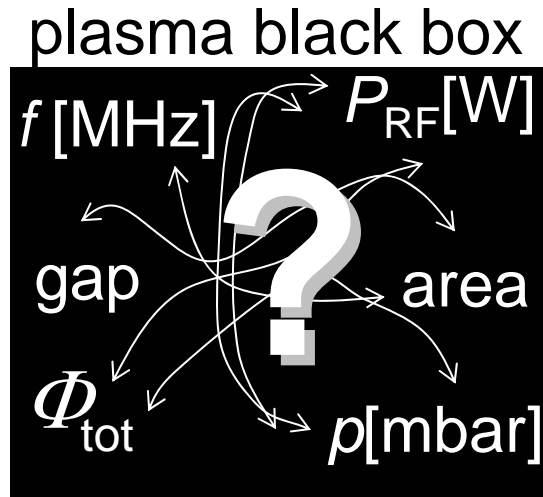
$$\boxed{\text{SiH}_4} \quad \begin{array}{c} \text{flow in} \\ \Phi_{\text{SiH}_4} \end{array} - \begin{array}{c} \text{lost by electron} \\ \text{impact} \\ \text{dissociation} \end{array} (kn_e + a) n_{\text{SiH}_4} = 0$$

$$\boxed{\text{SiH}_2} \quad \begin{array}{c} \text{produced by} \\ \text{dissociation} \end{array} kn_e n_{\text{SiH}_4} - \begin{array}{c} \text{lost by} \\ \text{deposition} \end{array} S n_{\text{SiH}_2} = 0$$

$$\boxed{\text{H}_2} \quad \begin{array}{c} \text{flow in} \\ \Phi_{\text{H}_2} \end{array} + \begin{array}{c} \text{produced by} \\ \text{surface} \\ \text{association} \end{array} \frac{1}{2} R n_{\text{H}} + \begin{array}{c} \text{produced} \\ \text{during} \\ \text{deposition} \end{array} S n_{\text{SiH}_2} - \begin{array}{c} \text{lost by} \\ \text{dissociation} \end{array} (k_{\text{H}} n_e + a) n_{\text{H}_2} = 0$$

$$\boxed{\text{H}} \quad \begin{array}{c} \text{produced by} \\ \text{dissociation of} \\ \text{silane} \end{array} 2kn_e n_{\text{SiH}_4} + \begin{array}{c} \text{produced by} \\ \text{dissociation of} \\ \text{hydrogen} \end{array} 2k_{\text{H}} n_e n_{\text{H}_2} - \begin{array}{c} \text{loss rate by} \\ \text{surface} \\ \text{association} \end{array} R n_{\text{H}} = 0$$

Depletion accounts for many of the plasma parameters



analytical
model

$$\frac{kn_e}{a_0} = \left(\frac{1}{1 - D} \right) \frac{D}{1 + c(1 - D)}$$

rate parameters in terms of
concentration parameters

$a_0 [s^{-1}]$ = inverse residence time = effective pumping speed = $6.1 \cdot 10^{-6} \frac{T_{\text{gas}} \Phi_{\text{total}}}{p \cdot \text{gap} \cdot \text{area}}$;

$kn_e [s^{-1}]$ = silane dissociation rate = plasma dissociation frequency = $F(P_{\text{RF}}, f [\text{MHz}])$;

c = silane input concentration, $\frac{\Phi_{\text{SiH}_4}}{\Phi_{\text{total}}}$.

Depletion scaling:

$D \uparrow$ if any of $\{p, \text{gap}, \text{area}, c, P_{\text{RF}}, f\} \uparrow$ &/or $\{F_{\text{total}}, T_{\text{gas}}\} \downarrow$

Plasma Sources Sci. Technol. **16** (2007) 679–696

Time-dependent 0-D analytical model :

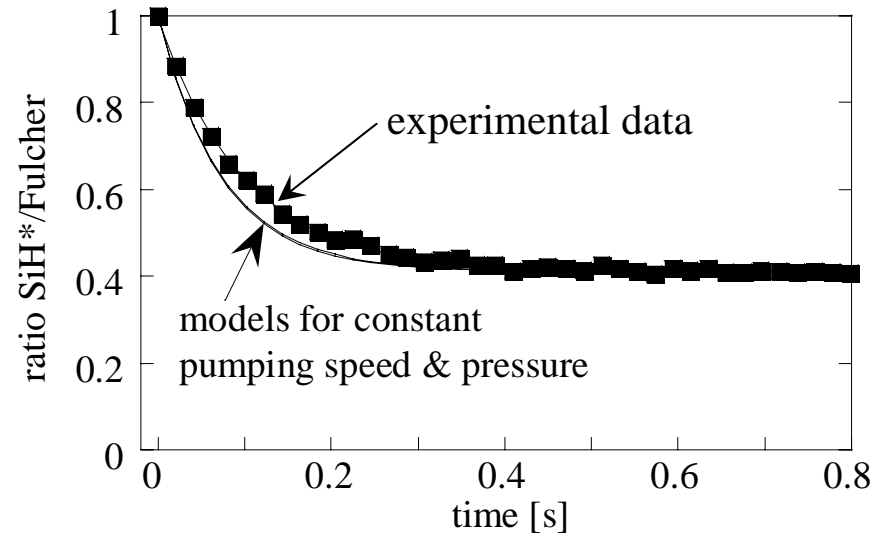
Assuming constant pumping speed, $a = a_0$,
the reaction rate balance for silane is

$$\text{SiH}_4 : \Phi_{\text{SiH}_4} - (kn_e + a_0)n_{\text{SiH}_4} = \frac{dn_{\text{SiH}_4}}{dt}$$

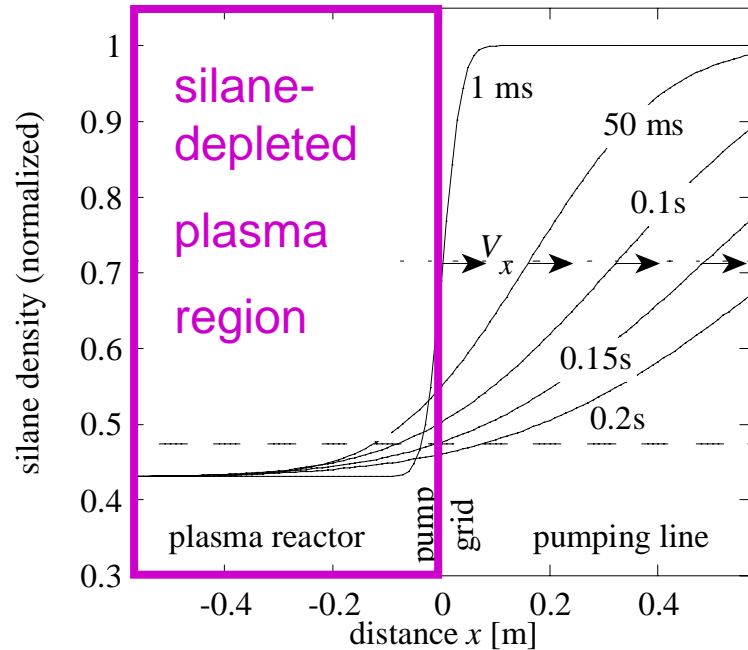
$$\therefore \frac{n_{\text{SiH}_4}(t)}{n_{\text{SiH}_4}(0)} = 1 - D \left[1 - \exp\left(-\frac{t}{\tau_{\text{eq}}}\right) \right],$$

where the plasma chemistry equilibration 1/e time, $\tau_{\text{eq}} = \frac{(1-D)}{a_0} = \tau_{\text{res}}(1-D)$.

For this example, $\tau_{\text{eq}} = \frac{(1-0.57)}{5.7} = 0.076 \text{ s}$. good agreement with experiment



- the 0-D model was used to predict the required time resolution ($\sim 20 \text{ ms}$) of a spectrometer for experiments.



initial silane density in reactor and pumping line

Plasma Sources Sci. Technol. **16** (2007) 679–696

The general three-dimensional binary transfer equation for the vacuum chamber, equation (23), can now be simplified to a dispersive axial flow equation [9]:

$$\frac{\partial n_{\text{SiH}_4}}{\partial t} + \bar{v}_x \frac{\partial n_{\text{SiH}_4}}{\partial x} - D_{AB} \frac{\partial^2 n_{\text{SiH}_4}}{\partial x^2} = 0, \quad (24)$$

Analytic solution:

$$\frac{n_{\text{SiH}_4}}{n_{\text{SiH}_4}^0} = 1 - \frac{D}{2} \text{erfc}(\zeta), \quad \zeta = \frac{x - \bar{v}_x t}{(4D_{AB}t)^{1/2}}$$

2) NUMERICAL CALCULATION OF ANALYTIC SOLUTION (eg Matlab programme)

- Green's function solution for (vacuum) potential distribution, rectangular reactor
- wavefield graphs, cylindrical reactor

Voltage uniformity on parallel plates, using Green's functions (vacuum)

L. Sansonnens *et al*, *Plasma Sources Sci. Technol.* **6**, 170 (1997)

Maxwell's equations reduce to a 2D driven Helmholtz equation (standing wave

$$(\nabla^2 + k^2)V(x) = i\omega\mu d J_z(x)$$

Green's function solution for a Dirac source:

$$(\nabla^2 + k^2)g(x; x_s) = \delta(x - x_s)$$

using eigenfunctions, defined

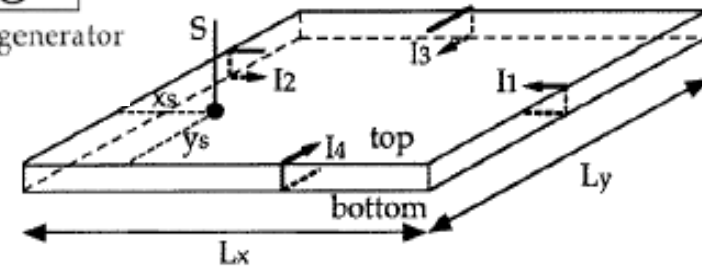
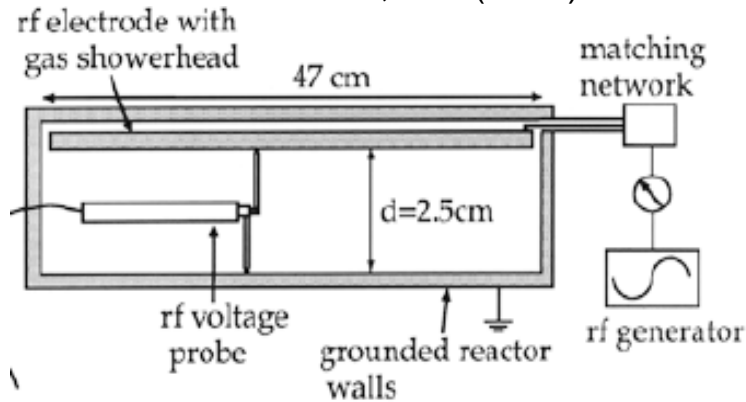
$$(\nabla^2 + k^2)\Phi_n(x) = \lambda_n \Phi_n(x)$$

express the Green's function

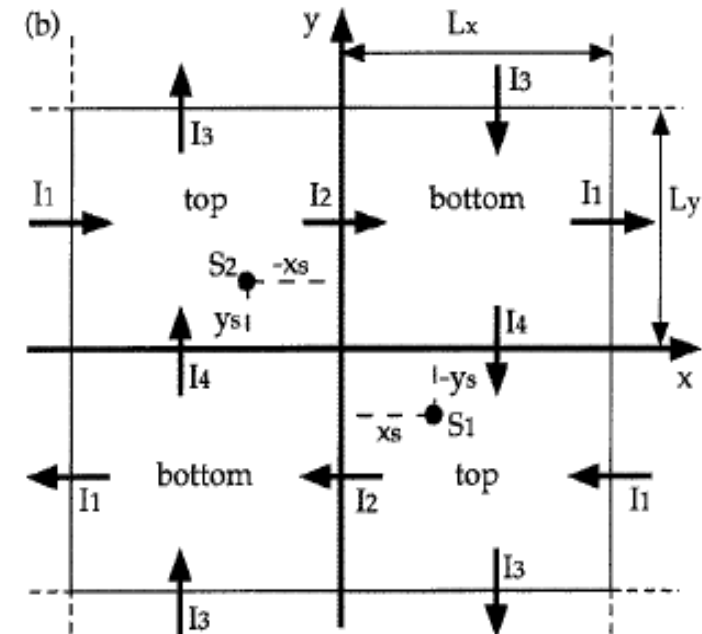
$$g(x; x_s) = \sum_n \frac{\Phi_n(x)\Phi_n(x_s)}{\lambda_n \langle \Phi_n, \Phi_n \rangle}$$

and the eigenfunctions are:

$$\Phi_n = \frac{\exp(i\pi(n_x x/L_x + n_y y/L_y))}{2\sqrt{L_x L_y}}$$



$$\langle \Phi_n, \Phi_n \rangle \equiv \int d\Omega \Phi_n^2$$



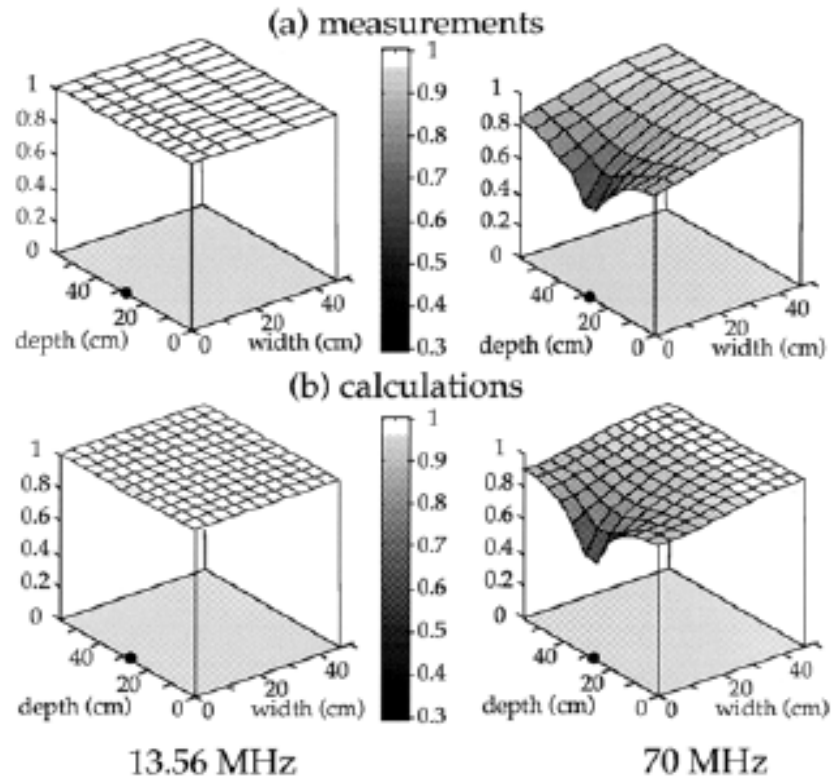
Voltage uniformity on parallel plates, using Green's functions (vacuum)

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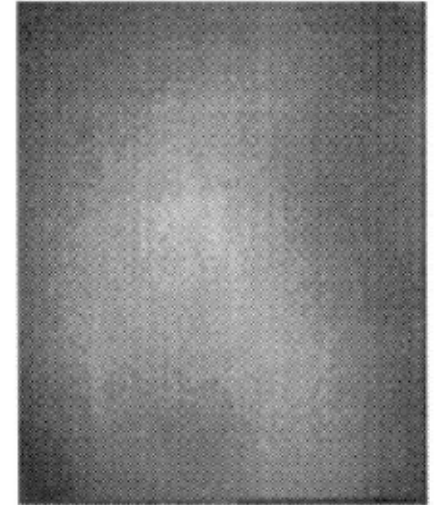
ÉCOLE POLYTECHNIQUE
FÉDÉRALE DE LAUSANNE

thin film interferograms
(37 cm x 47 cm
substrate)

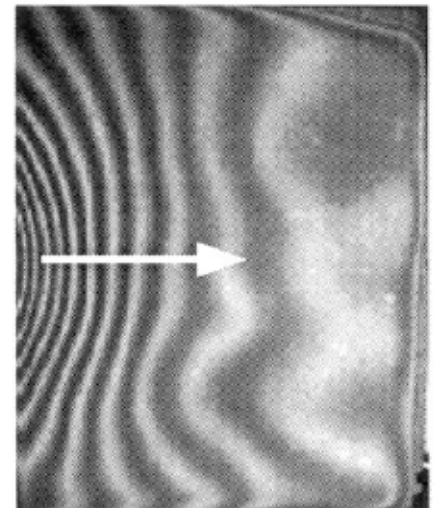
Green's function
model with
numerical
calculation
for voltage
distribution in
vacuum



(a) 13.56 MHz



(b) 70 MHz

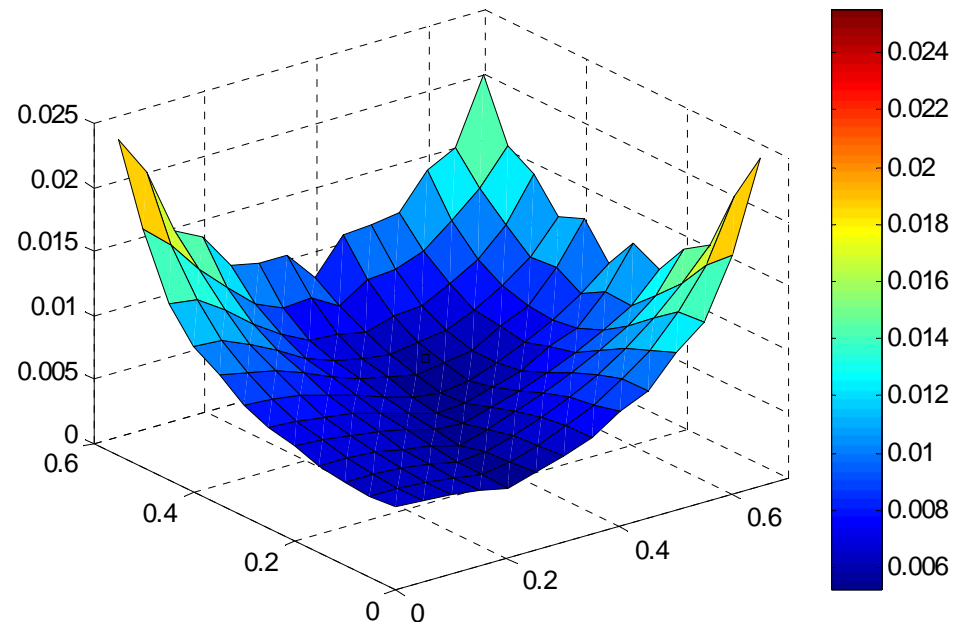
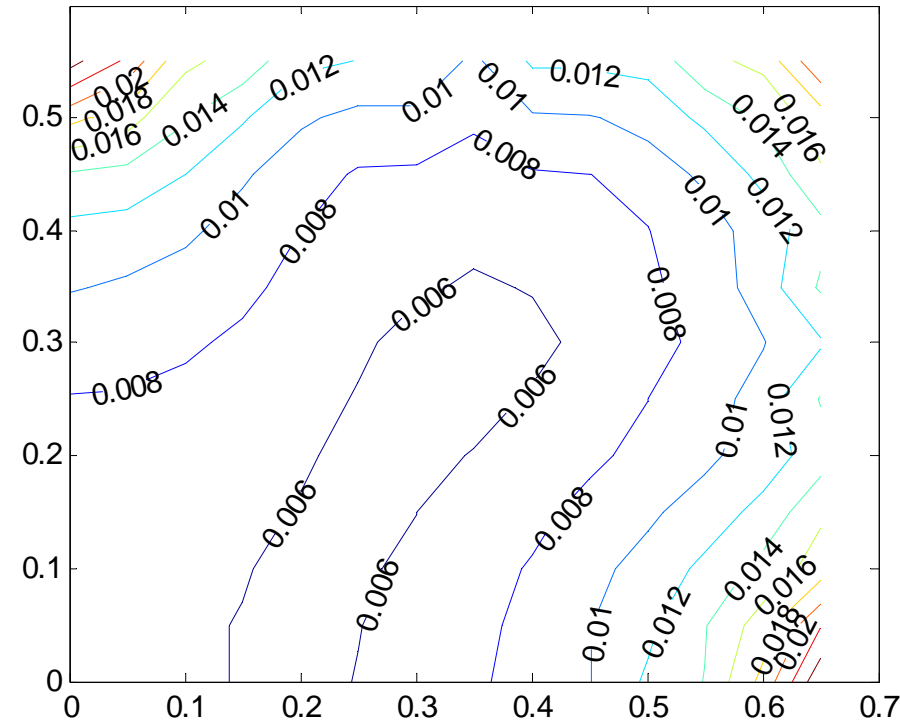


Estimate of best RF connection positions, using Green's functions (vacuum)

ÉCOLE POLYTECHNIQUE
LAUSANNE

Define voltage non-uniformity $\Delta V = \frac{V_{\max} - V_{\min}}{V_{\max} + V_{\min}}$, electrode size 1.4 x 1.2 m, $f = 13.56$ MHz.

Plots of voltage non-uniformity vs RF connection position on a quadrant



Position for best uniformity @ 13.56 MHz
4 connections: $x \sim \pm 0.3$ m; $y \sim \pm 0.25$ m;
 $\Delta V \sim 0.0053$

ions (vacuum)

USANNE

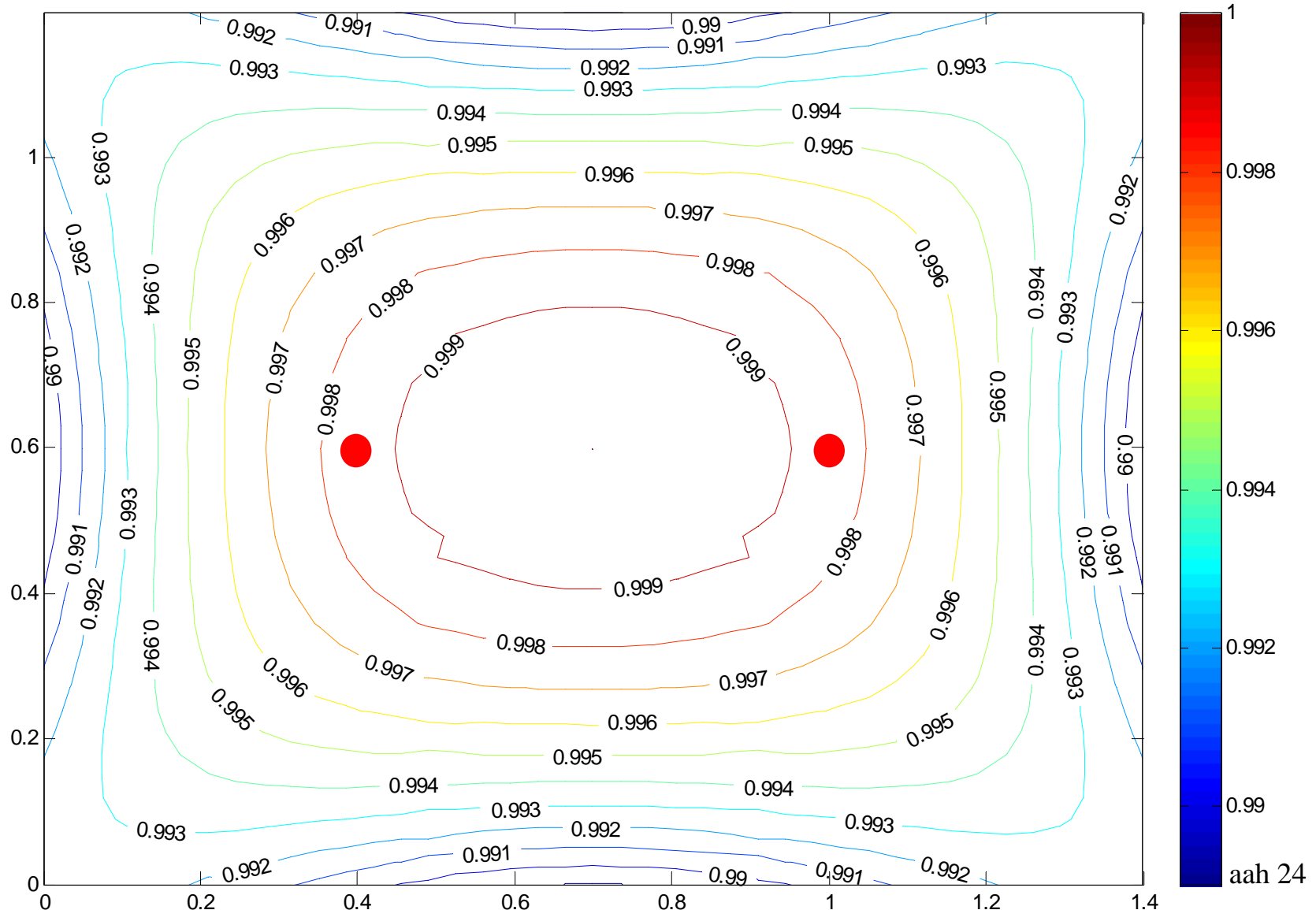
USANNE



Estimate of best RF connection positions, using Green's functions (vacuum)

ÉCOLE POLYTECHNIQUE
DE LAUSANNE

Voltage contour plot for 2 sources in best positions: $x = \pm 0.2$ m, $y = 0$ m; 13.56 MHz



Maxwell's equations

$$\begin{aligned}\frac{\partial H_\phi}{\partial z} &= -j\omega\epsilon_0 E_r, \\ \frac{1}{r} \frac{\partial(r H_\phi)}{\partial r} &= j\omega\epsilon_0 E_z, \\ \frac{\partial E_r}{\partial z} - \frac{\partial E_z}{\partial r} &= -j\omega\mu_0 H_\phi\end{aligned}$$

field equation

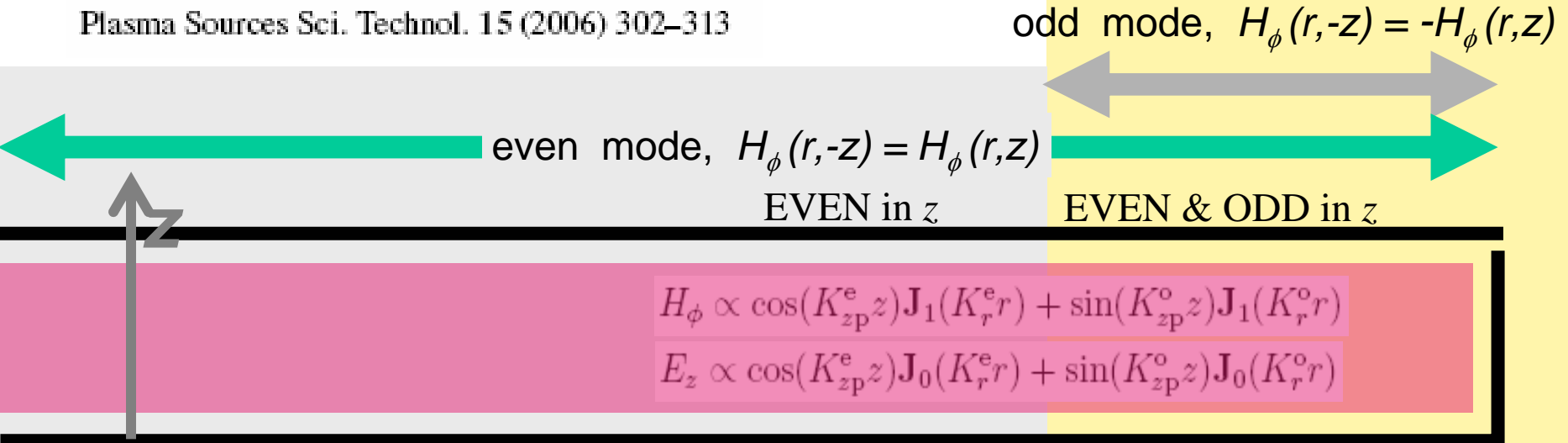
$$\frac{1}{\epsilon} \left[\frac{\partial^2 H_\phi}{\partial r^2} + \frac{1}{r} \frac{\partial H_\phi}{\partial r} - \frac{1}{r^2} H_\phi \right] + \frac{\partial}{\partial z} \left[\frac{1}{\epsilon} \frac{\partial H_\phi}{\partial z} \right] + k_0^2 H_\phi = 0$$

general field solution for top sheath (here),
plasma and bottom sheath regions

$$\begin{aligned}H_\phi &= \sum_{n=0}^{\infty} \frac{D_n^c}{K_{zs,n}^c} \cos(K_{zs,n}^c(l-z)) J_1(K_{r,n}^c r) \\ &\quad + \sum_{n=0}^{\infty} \frac{D_n^o}{K_{zs,n}^o} \cos(K_{zs,n}^o(l-z)) J_1(K_{r,n}^o r), \\ E_z &= \frac{1}{j\omega\epsilon_0} \sum_{n=0}^{\infty} \frac{D_n^c K_{r,n}^c}{K_{zs,n}^c} \cos(K_{zs,n}^c(l-z)) J_0(K_{r,n}^c r) \\ &\quad + \frac{1}{j\omega\epsilon_0} \sum_{n=0}^{\infty} \frac{D_n^o K_{r,n}^o}{K_{zs,n}^o} \cos(K_{zs,n}^o(l-z)) J_0(K_{r,n}^o r) \\ E_r &= \frac{-1}{j\omega\epsilon_0} \sum_{n=0}^{\infty} D_n^c \sin(K_{zs,n}^c(l-z)) J_1(K_{r,n}^c r) \\ &\quad - \frac{1}{j\omega\epsilon_0} \sum_{n=0}^{\infty} D_n^o \sin(K_{zs,n}^o(l-z)) J_1(K_{r,n}^o r).\end{aligned}$$

find even and odd modes for symmetric and non-symmetric reactor, PTO

Plasma Sources Sci. Technol. 15 (2006) 302–313



the dispersion relation of the even mode reproduces the intuitive equivalent circuit of the standing wave effect:

$$(K_{r,0}^e)^2 \approx k_0^2 \frac{(1 + d/s)}{(1 + d/(\epsilon_p s))}$$

$$= -j\omega L_{\text{gap}} \left[\frac{2}{j\omega C_s} + \frac{1}{Y_p} \right]^{-1}$$

the dispersion relation of the odd mode reproduces the intuitive equivalent circuit of the telegraph effect:

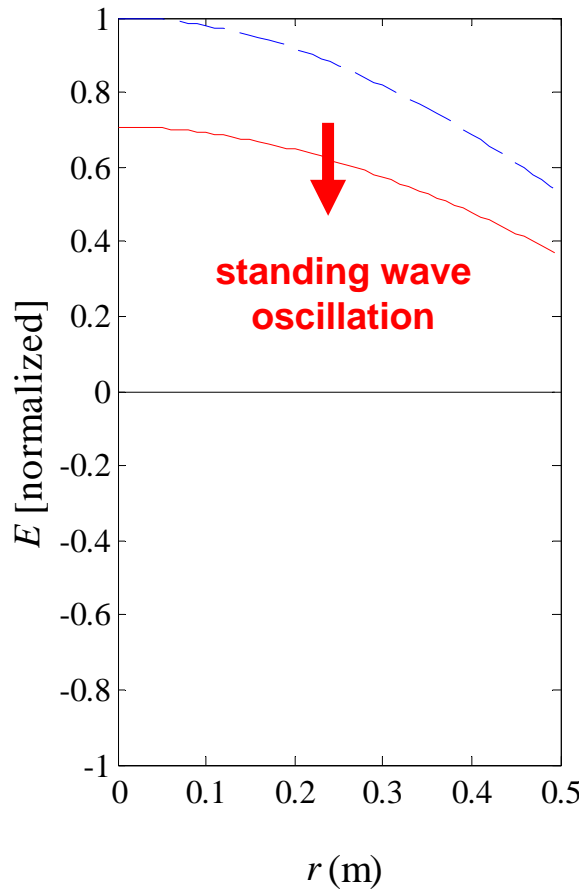
$$(K_{r,0}^o)^2 \approx k_0^2 - \frac{1}{\epsilon_p s d}$$

$$= -[j\omega L_s + Z_{\text{sq}}] (2j\omega C_s)$$

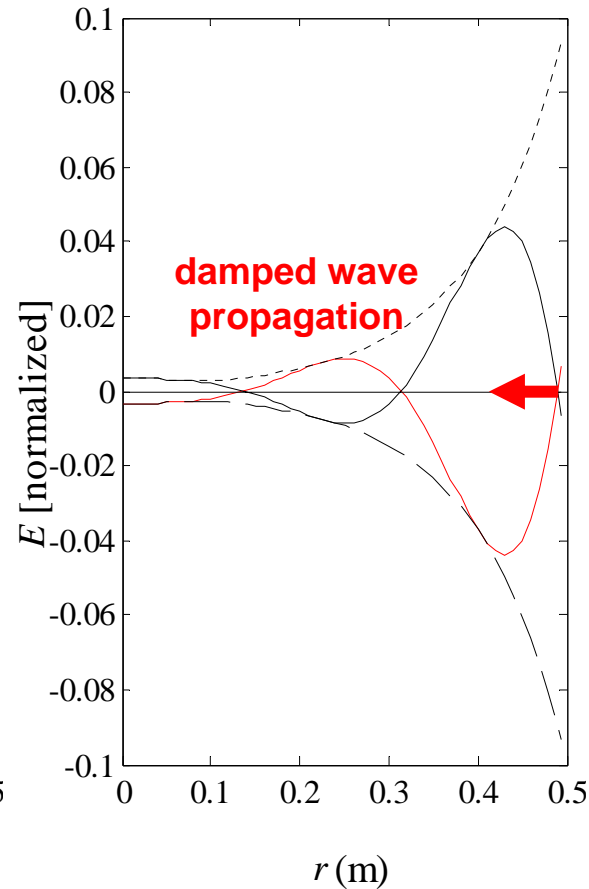
Wavefield analytic solution in a cylindrical reactor with plasma, solution plotted using Matlab

Plasma Sources Sci. Technol. 15 (2006) 302–313

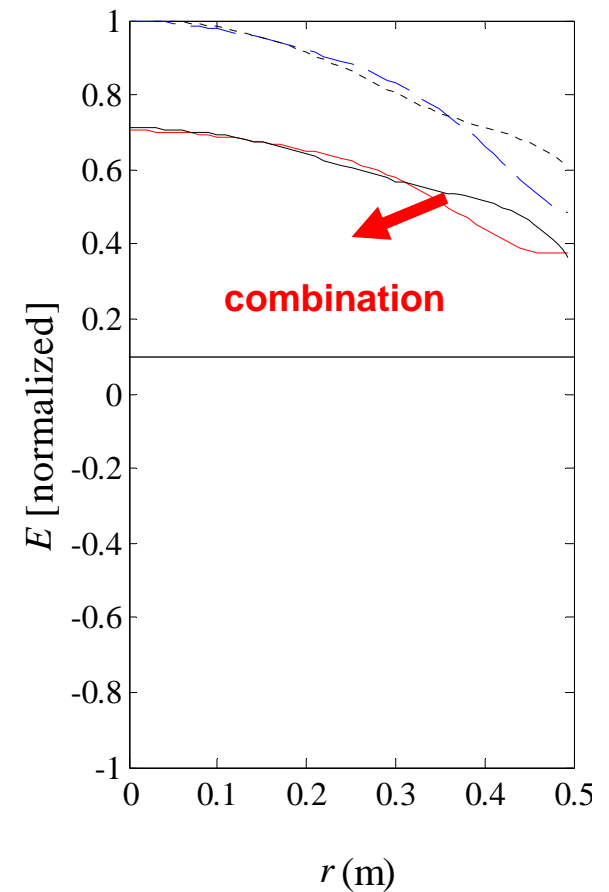
EVEN MODE
standing wave effect



ODD MODE
telegraph effect **x10**



PLASMA RESPONSE
combined effect



3) NUMERICAL SOLUTION OF EQUATIONS (eg FlexPDE partial differential equation solver)

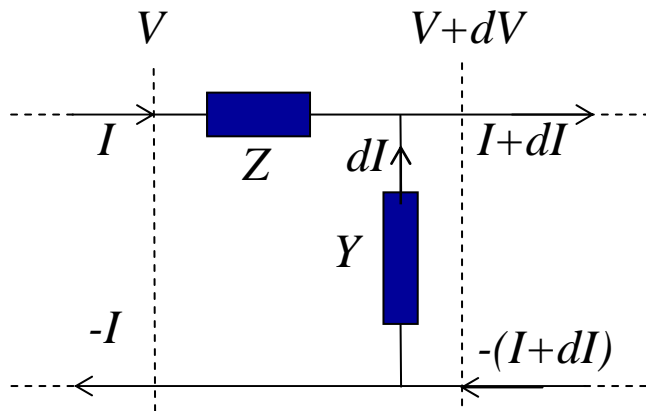
- rectangular lens standing wave correction
- 2D rectangular telegraph effect
- plasma 2D benchmark in Comsol

Rectangular lens and standing wave correction

JOURNAL OF APPLIED PHYSICS 97, 063304 (2005)

L. Sansonnens

Reminder of
cylindrical electrodes



Repeat for
rectangular electrodes

Kirchoff's laws: $\frac{dV}{dr} = -IZ$, $\frac{dI}{dr} = -YV$.

Substitute for I (or for V):

$$\frac{d^2V}{dr^2} = \left(\frac{1}{Z} \frac{dZ}{dr} \right) \frac{dV}{dr} + YZV, \text{ which is the}$$

general voltage wave equation for a cylindrical transmission line.

Kirchoff's laws: $\nabla_t V = -Z\mathbf{J}_s$, $\nabla_t \cdot \mathbf{J}_s = -YV + J_z$

Substitute for J (or for V):

$$\nabla_t^2 V - \frac{\nabla_t Z}{Z} \cdot \nabla_t V - YZV = -ZJ_z.$$

which is the general voltage wave equation for a 2D quasiplanar circuit

Rectangular lens and standing wave correction

JOURNAL OF APPLIED PHYSICS 97, 063304 (2005) L. Sansonnens

1425 J. Vac. Sci. Technol. A 24(4), Jul/Aug 2006

Solve two wave equations:

for the voltage across the top, $V_{\text{top}}(x, y)$

and the voltage across the bottom, $V_{\text{bot}}(x, y)$.

Wave equation for the top gap (planar):

$$\nabla^2 V_{\text{top}} + k_0^2 V_{\text{top}} = f(x, y),$$

where $k_0^2 = \omega^2/c^2$, f is the voltage source.

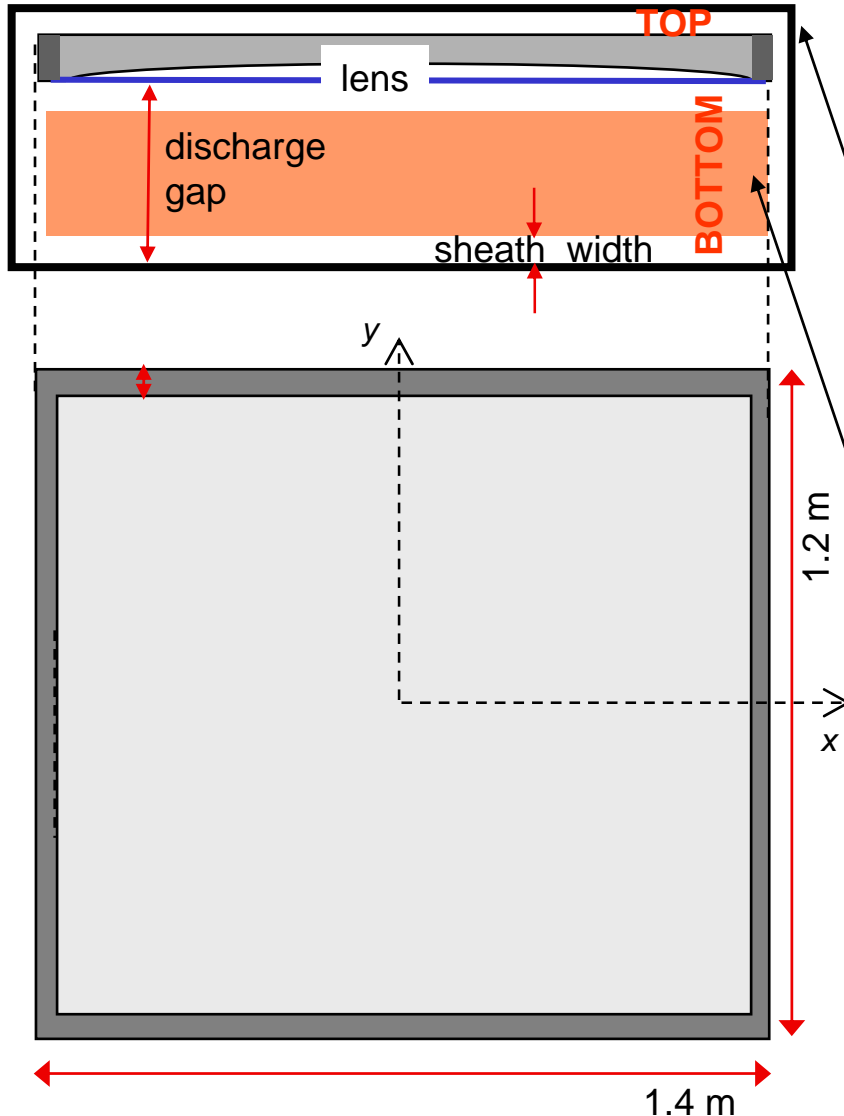
Wave equation for the bottom gap (curved):

$$\nabla^2 V_{\text{bot}} - \frac{\nabla d(x, y)}{d(x, y)} \cdot \nabla V_{\text{bot}} + k_{\text{eff}}^2 V_{\text{bot}} = 0,$$

where $k_{\text{eff}}^2 = \omega^2 \epsilon_{\text{eff}}(x, y)/c^2$,

$\epsilon_{\text{eff}}(x, y)$ accounts for the plasma, sheath and lens,

$d(x, y)$ accounts for the changing gap inductance per unit area, $Z(x, y) = j\mu_0\omega d(x, y)$.



Rectangular lens and standing wave correction

JOURNAL OF APPLIED PHYSICS 97, 063304 (2005)

L. Sansonnens

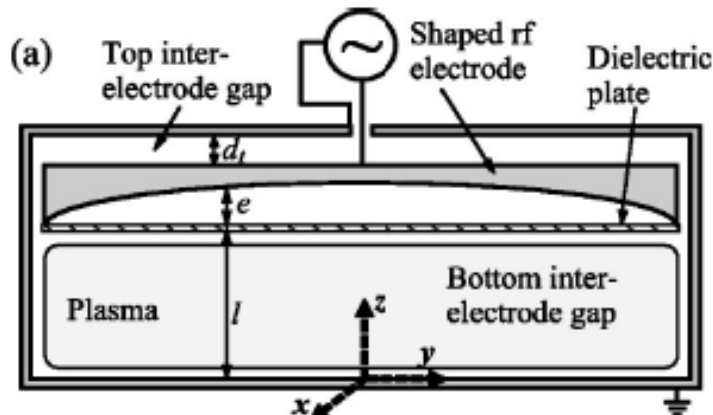
1425 J. Vac. Sci. Technol. A 24(4), Jul/Aug 2006

...along with the boundary conditions for voltage and surface current continuity:

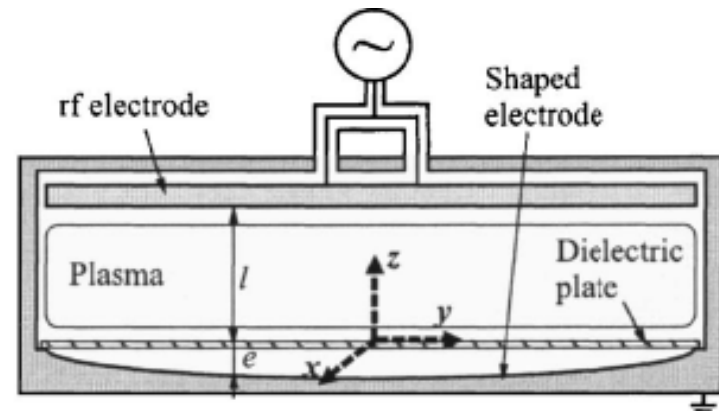
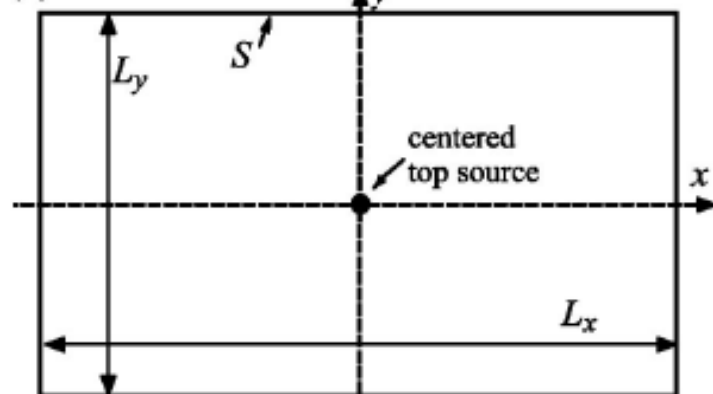
$$V_{\text{top}} = V_{\text{bot}} \quad \text{and} \quad \frac{1}{Z_{\text{top}}} \frac{\partial V_{\text{top}}}{\partial \underline{n}} = \frac{1}{Z_{\text{bot}}} \frac{\partial V_{\text{bot}}}{\partial \underline{n}}.$$

For RECTANGULAR electrodes,

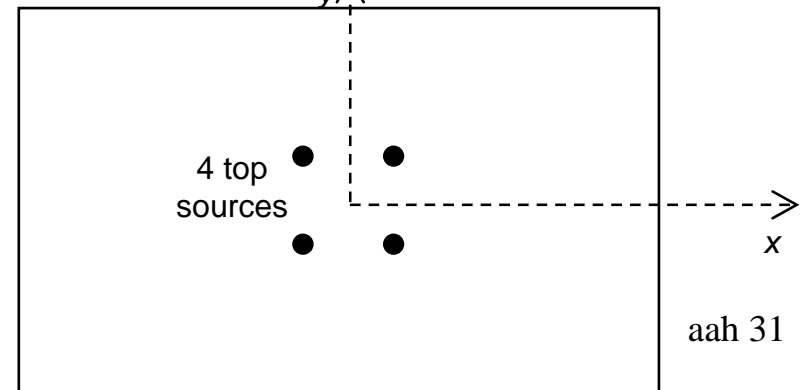
the boundary conditions, and therefore the lens shape, depend on the PLASMA.



(b) **single source, RF lens electrode**



multiple source, ground lens electrode



Rectangular lens shape: standing wave correction

L. Sansonnens

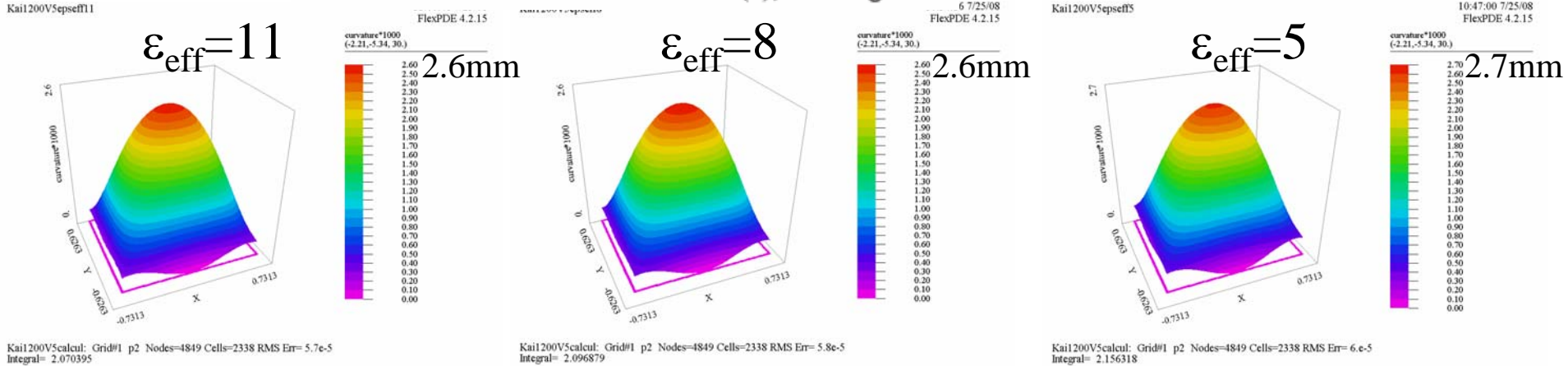
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J. Vac. Sci. Technol. A 24(4), Jul/Aug 2006

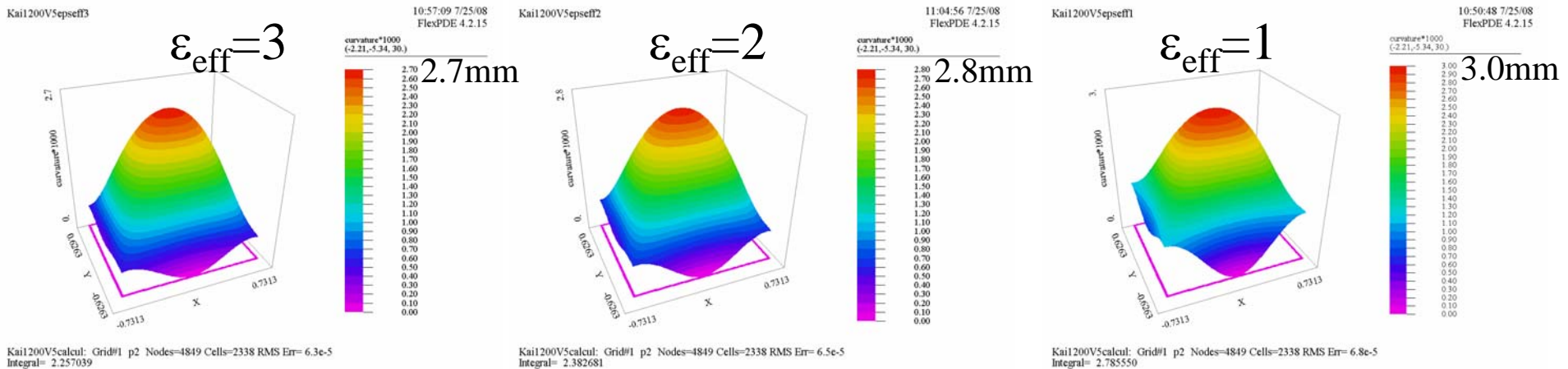
6 7/25/08

Kai1200V5sepf3

10:47:00 7/25/08
FlexPDE 4.2.15



Laurent Sansonnens programme using FlexPDE solver. Luckily, the lens shape is not very sensitive to plasma.



The **boundary conditions** depend on the top gap and sheaths.
Only for *cylindrical* lens is the shape independent of plasma.

JOURNAL OF APPLIED PHYSICS **97**, 123308 (2005)
and J. Appl. Phys. **96**, 5429 (2004)

Injection of RF current from a **sidewall** along the plasma.

Equivalent circuit of the plasma and sheaths gives the 2D telegraph equation:

$$\nabla^2 V - L_{sq} C' \frac{\partial^2 V}{\partial t^2} - R_{sq} C' \frac{\partial V}{\partial t} = 0$$

The 1D analytic solution is:

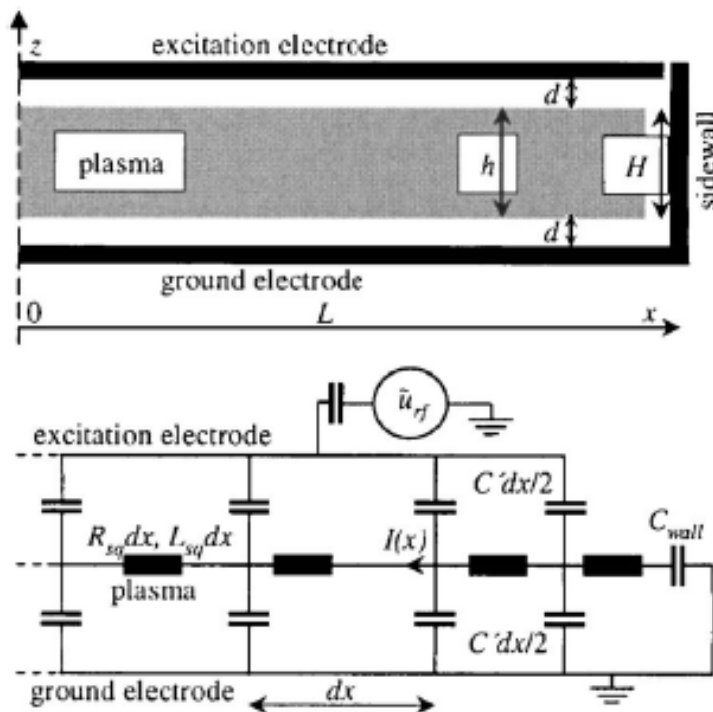
$$V = V_1 e^{-x/\delta} e^{i(\omega t - x/\delta)}$$

with damping length:

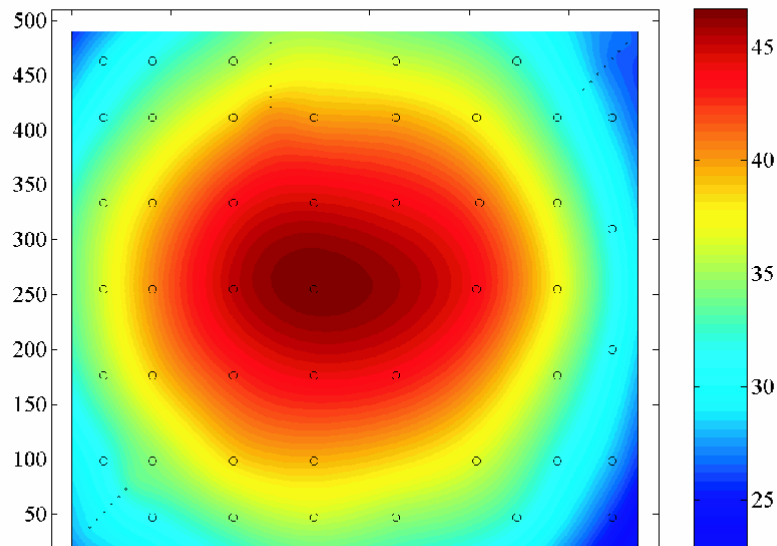
$$\delta = \sqrt{\frac{2}{\omega R_{sq} C'}} = \omega_{pe} \sqrt{\frac{hd}{\omega \nu_m}},$$

The equation to be solved numerically is

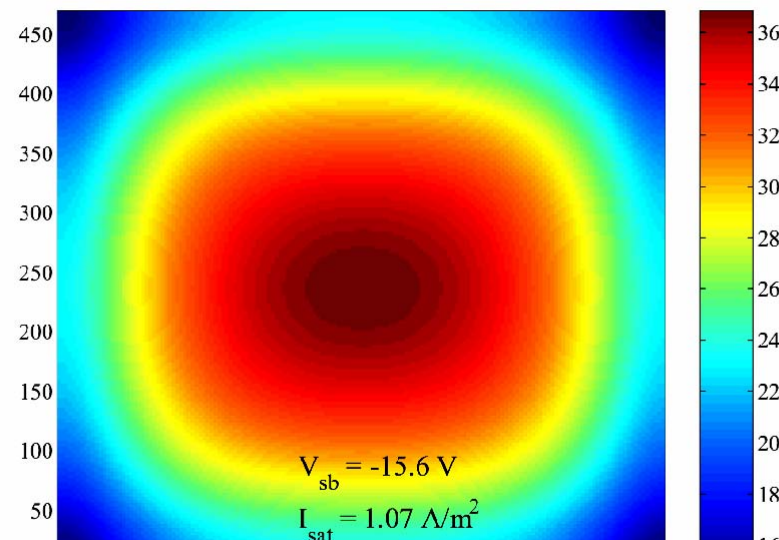
$$\nabla^2 \tilde{v} = \frac{2}{\delta^2} \left(i - \frac{\omega}{\nu_m} \right) \tilde{v}, \quad \text{for 2D}$$



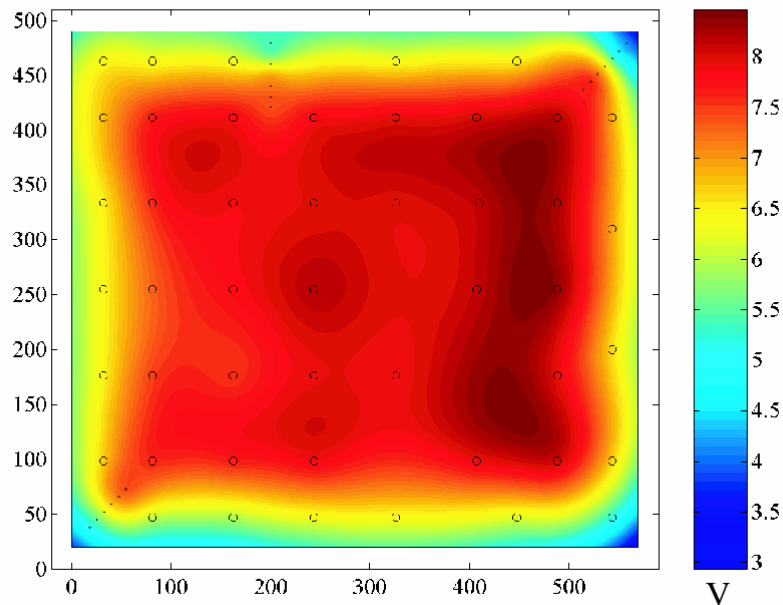
interpolation of probe measurements
voltage measurement



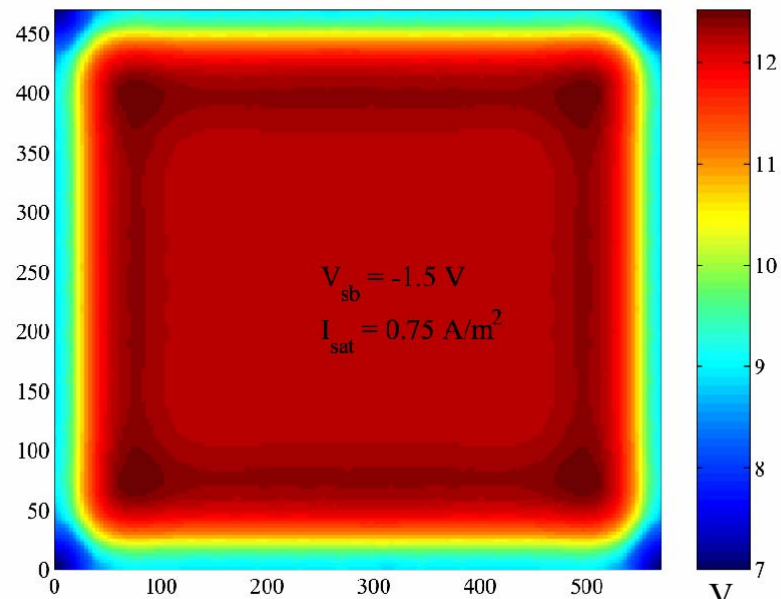
numerical solution of telegraph equation
voltage simulation



voltage measurement



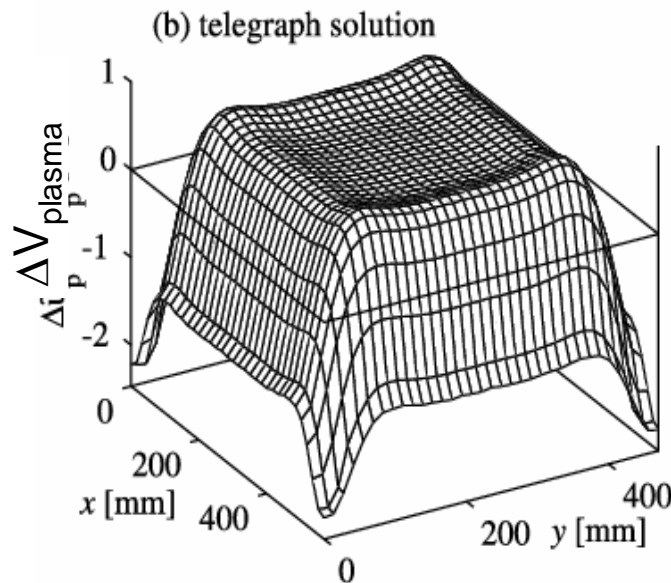
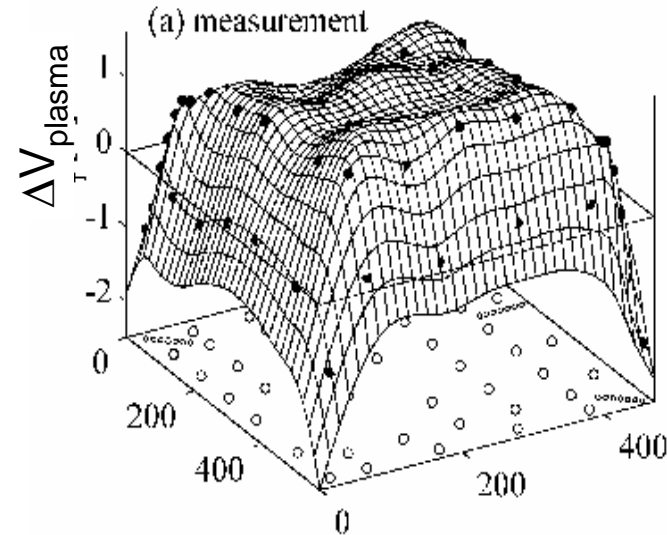
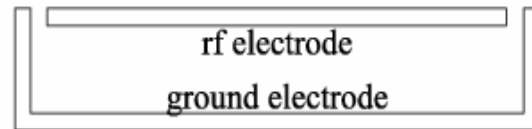
voltage simulation



2D calculation of the telegraph effect in rectangular reactors

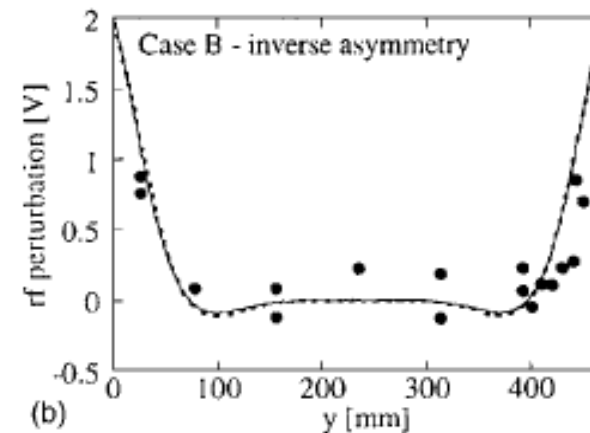
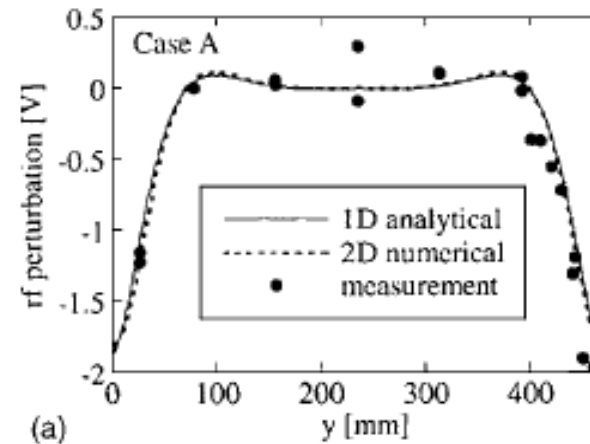
JOURNAL OF APPLIED PHYSICS 97, 123308 (2005)

Case A



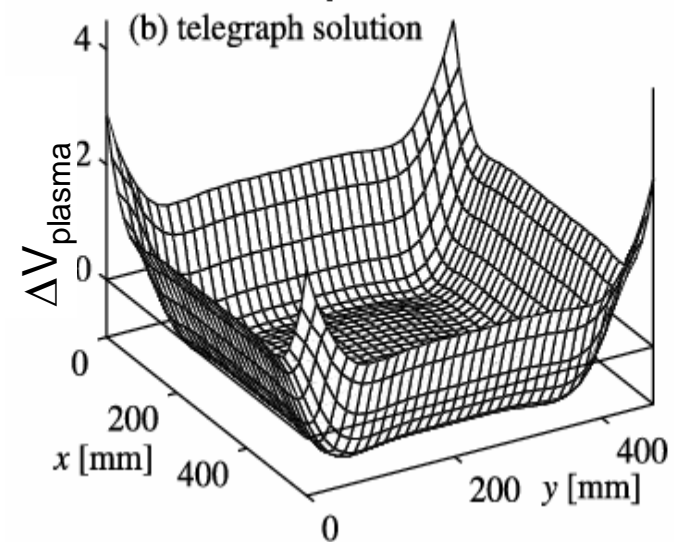
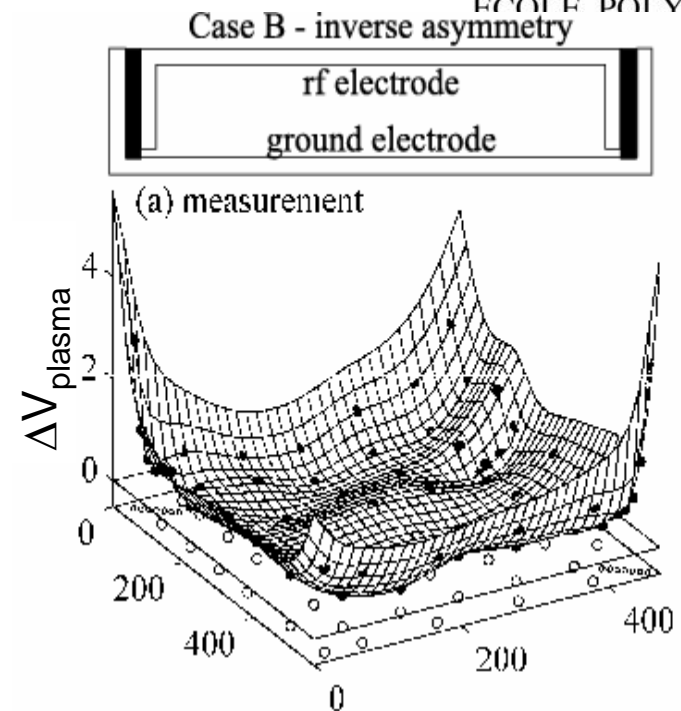
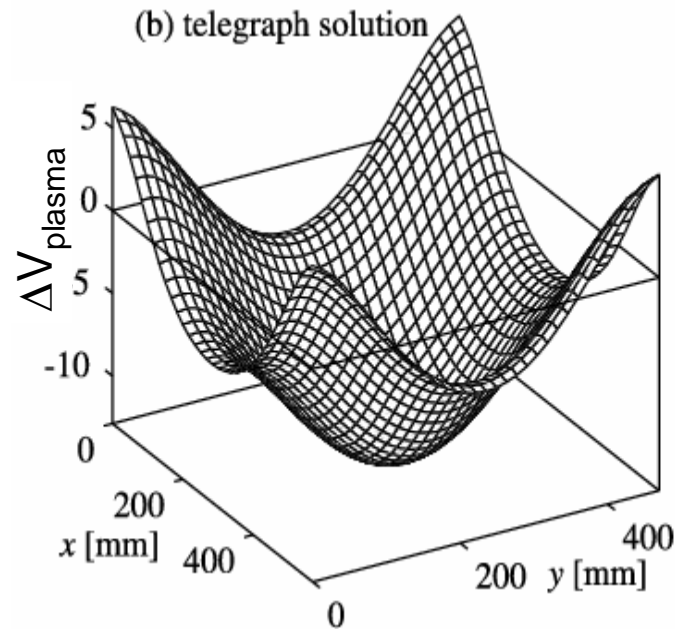
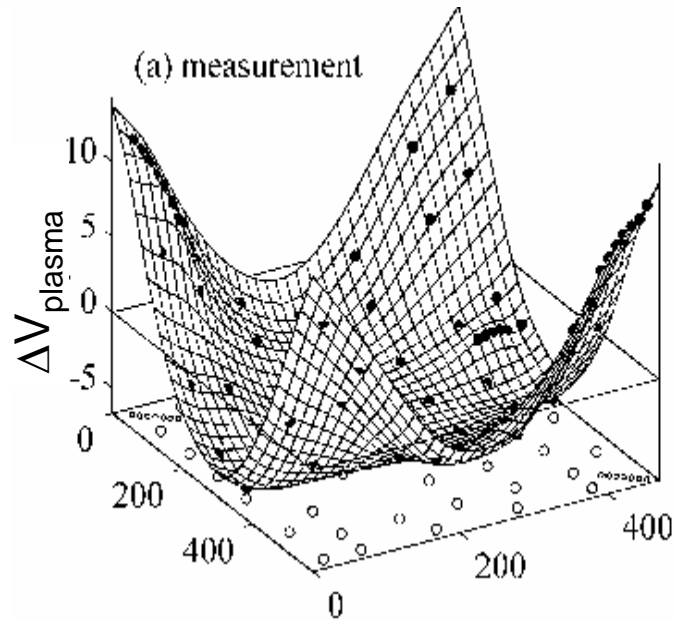
At mid-point, good correspondence of

- 1D analytic solution
- 2D numerical solution
- experimental measurements

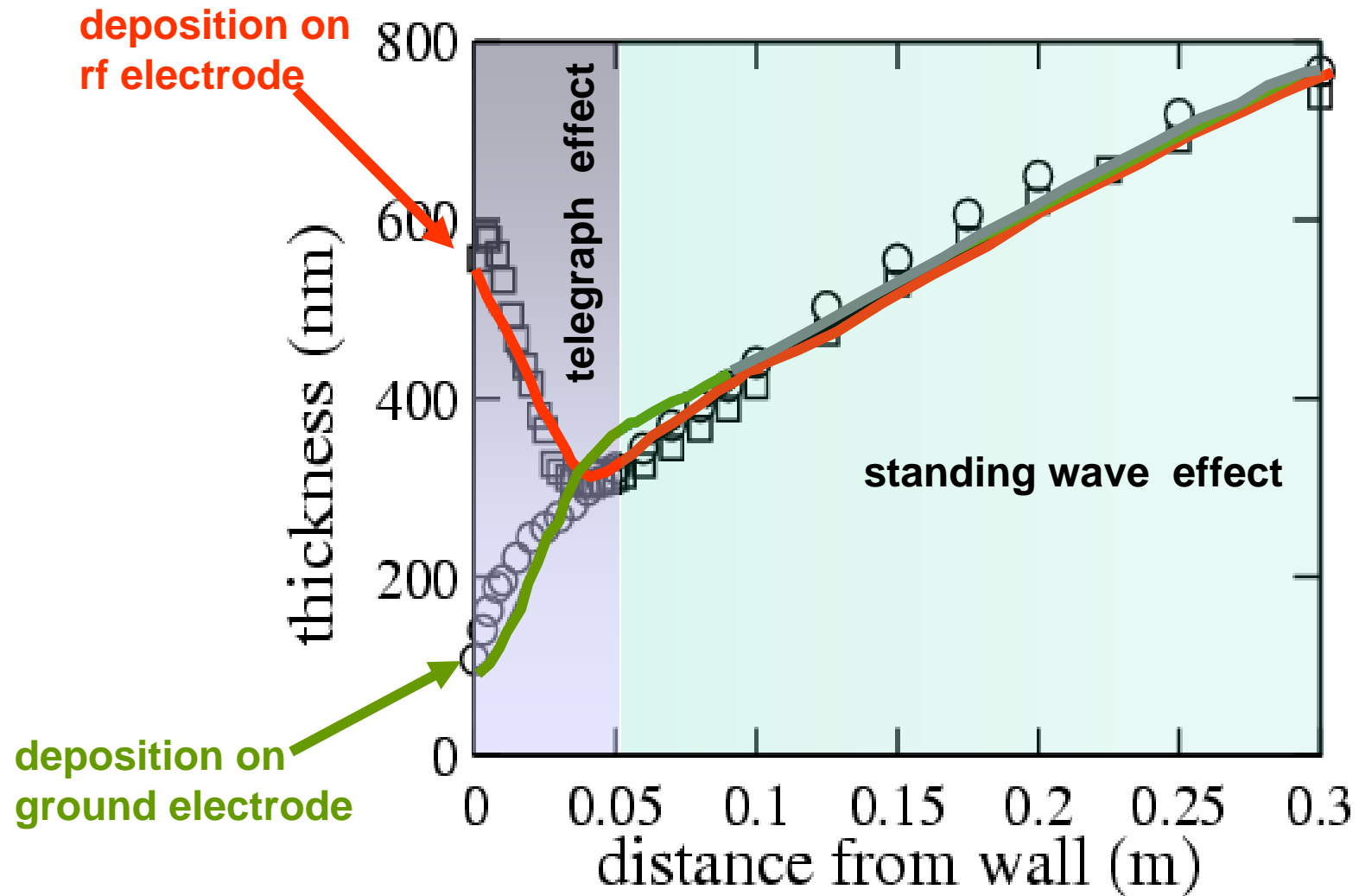


2D calculation of the telegraph effect in rectangular reactors

JOURNAL OF APPLIED PHYSICS 97, 123308 (2005)



2D calculation of film thickness profiles



electron continuity: $\frac{\partial n_e}{\partial t} + \nabla \cdot \underline{\Gamma}_e = k_{\text{ion}} n_e N; \quad \underline{\Gamma}_e = -\mu_e n_e \underline{E} - D_e \nabla n_e$

ion continuity: $\frac{\partial n_i}{\partial t} + \nabla \cdot \underline{\Gamma}_i = k_{\text{ion}} n_e N; \quad \underline{\Gamma}_i = \mu_i n_i \underline{E} - D_i \nabla n_i$

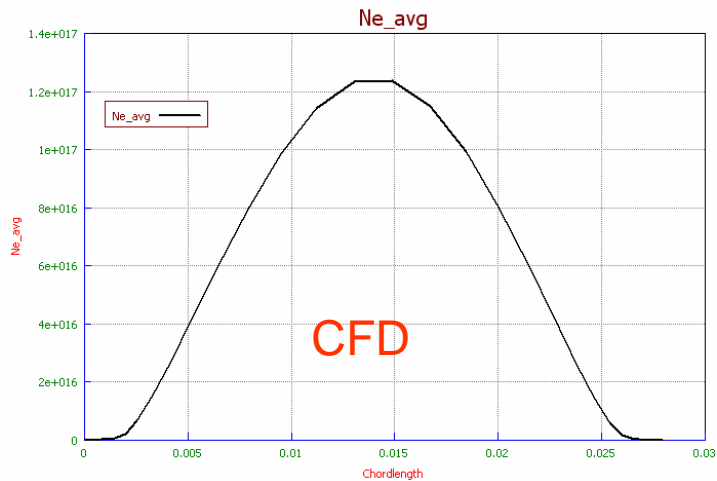
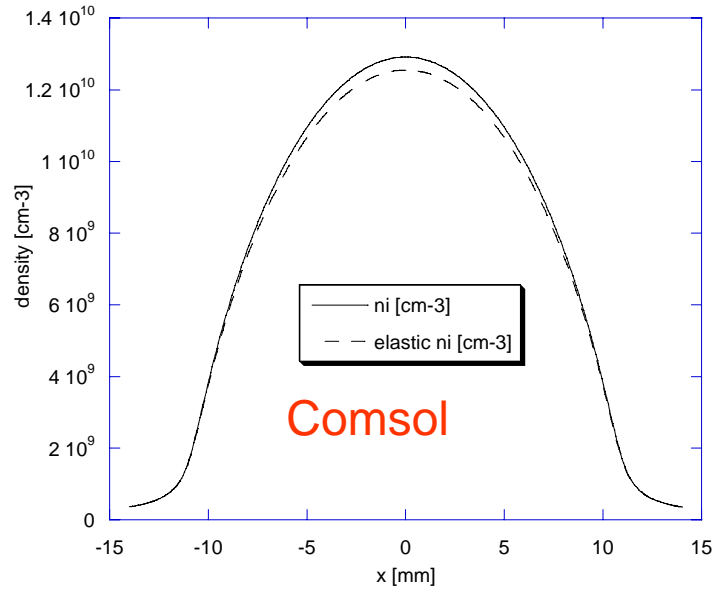
electron energy continuity; $(n_e \varepsilon)$ is the energy density in $\text{eV} \cdot \text{m}^{-3}$:

$$\frac{\partial (n_e \varepsilon)}{\partial t} + \nabla \cdot \underline{\Gamma}_w = -\underline{\Gamma}_e \cdot \underline{E} - K_{\text{loss}} n_e N; \quad \underline{\Gamma}_w = -\frac{5}{3} \mu_e (n_e \varepsilon) \underline{E} - \frac{5}{3} D_e \nabla (n_e \varepsilon);$$

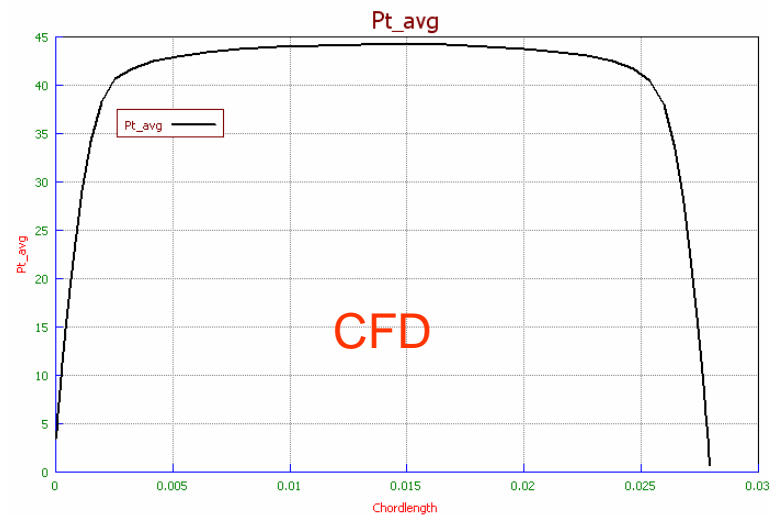
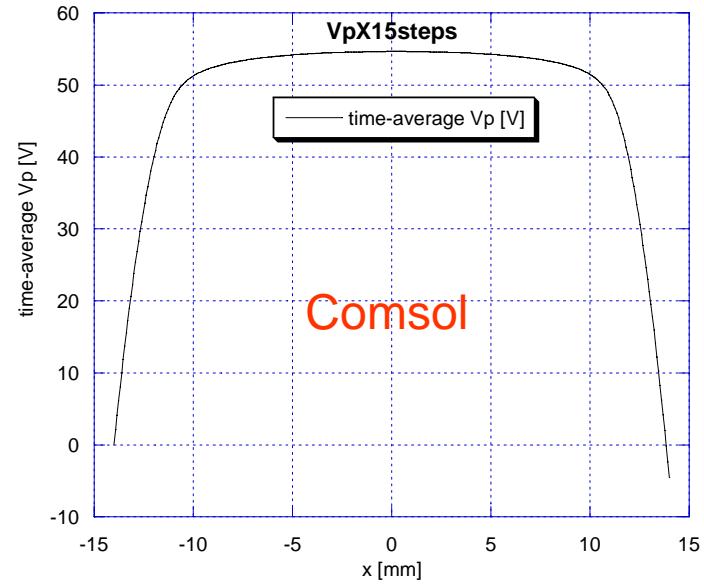
$$-\underline{\Gamma}_e \cdot \underline{E} = \mu_e n_e (E_x^2 + E_y^2) + D_e \left(\frac{\partial n_e}{\partial x} E_x + \frac{\partial n_e}{\partial y} E_y \right).$$

Poisson's equation: $\nabla^2 V = -\frac{e}{\varepsilon_0} (n_i - n_e); \quad \underline{E} = -\nabla V$

Time-averaged density profiles



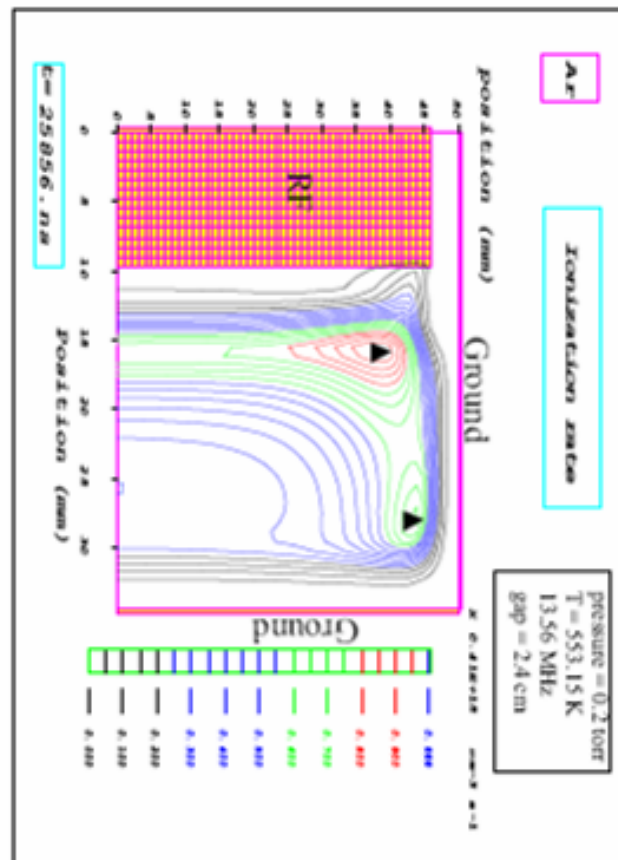
Time-averaged plasma potential profiles

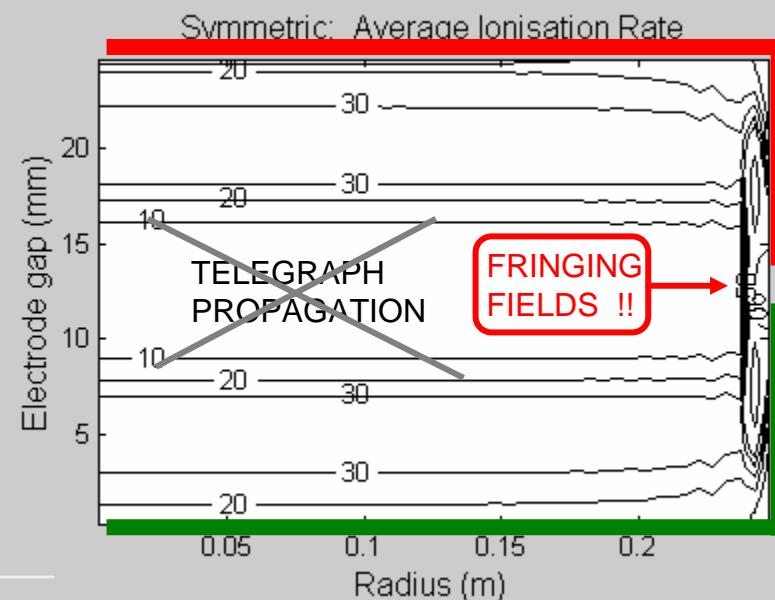
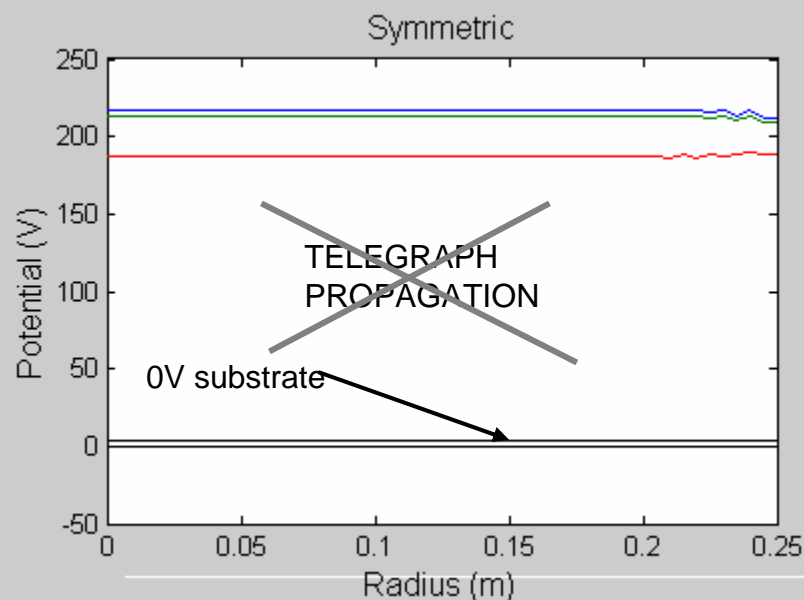
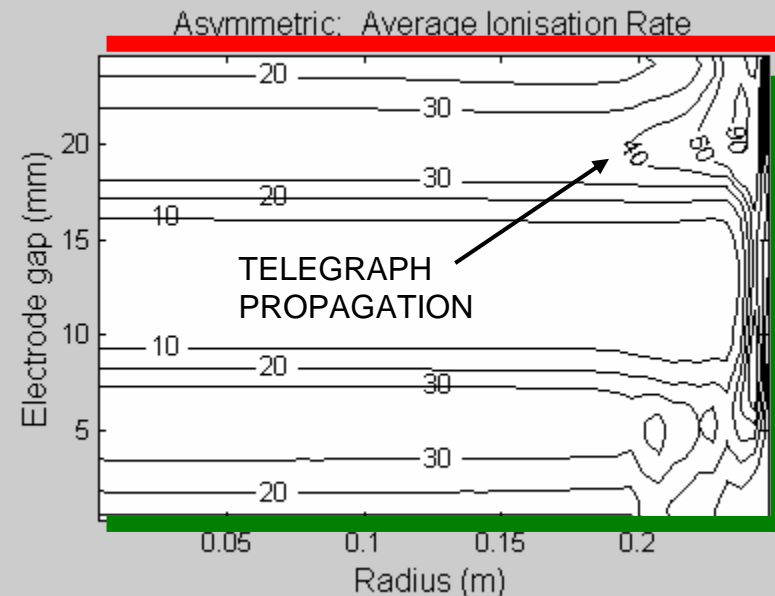
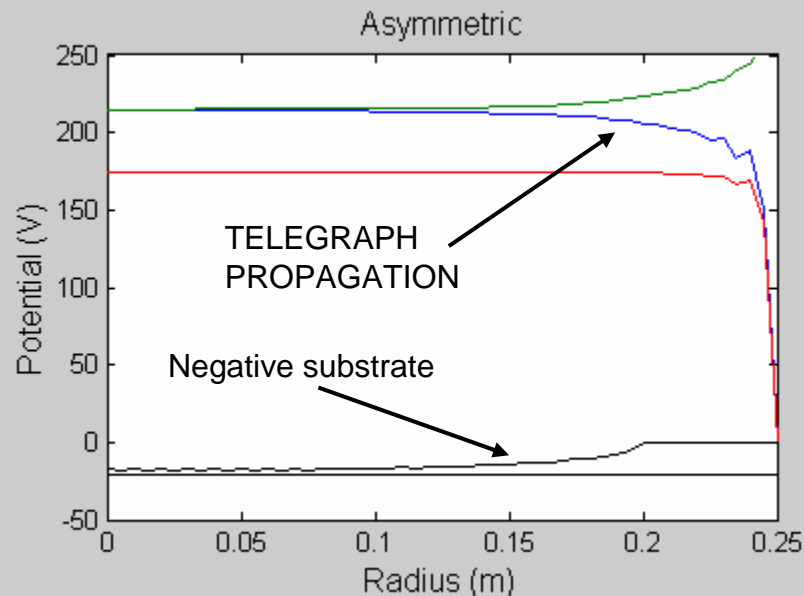


4) NUMERICAL SIMULATION (eg Siglo-RF; and COMSOL Multiphysics finite elements)

- Siglo 2D plasma simulation: edge and telegraph
- CFD showerhead uniformity, compare 0D plasma chemistry
- Comsol gas flow, edge speed

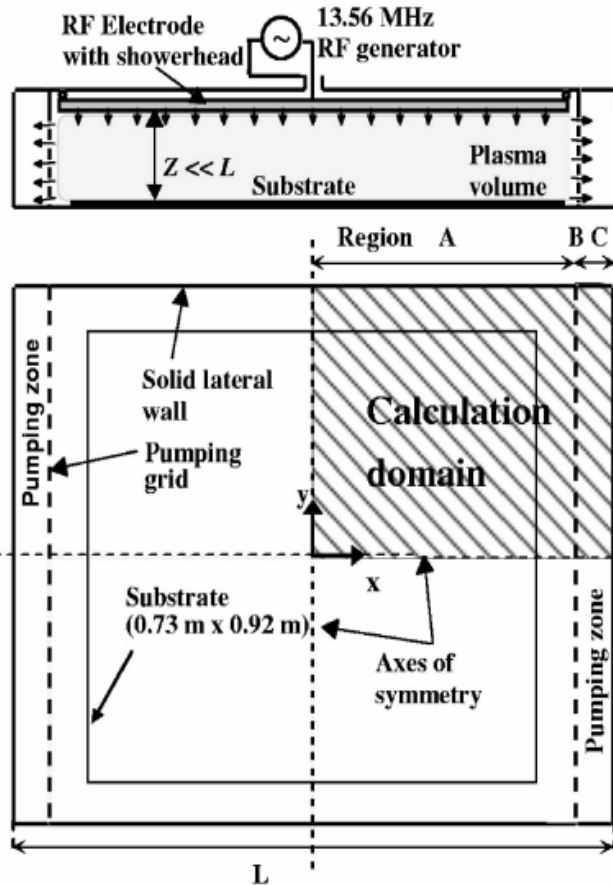
Siglo2D simulation of plasma ionization rate for a standard edge geometry.





CFD-ACE

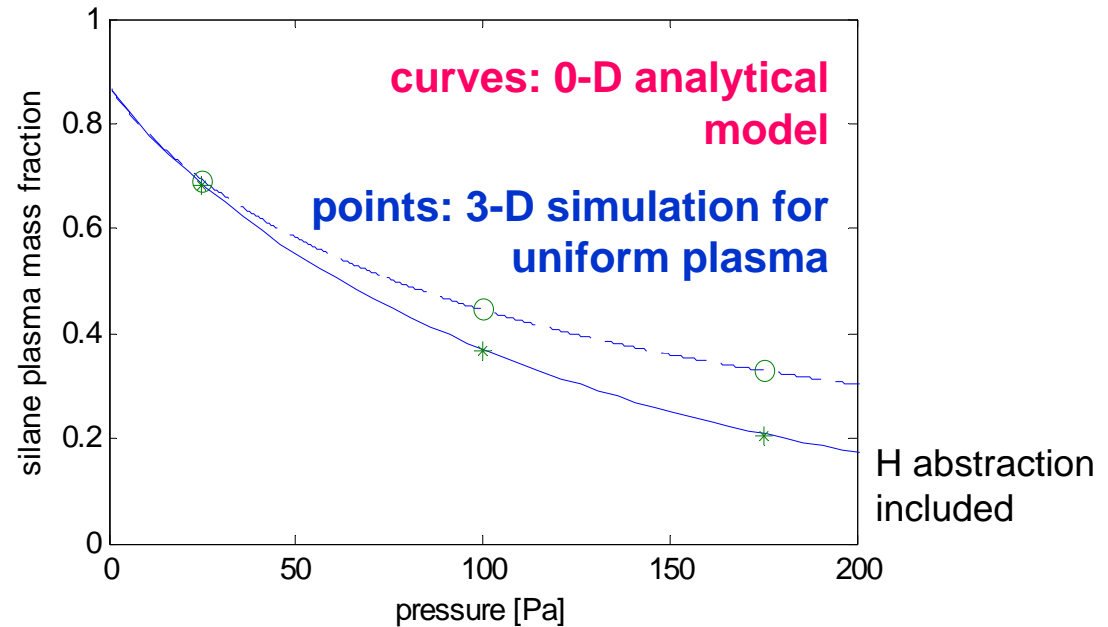
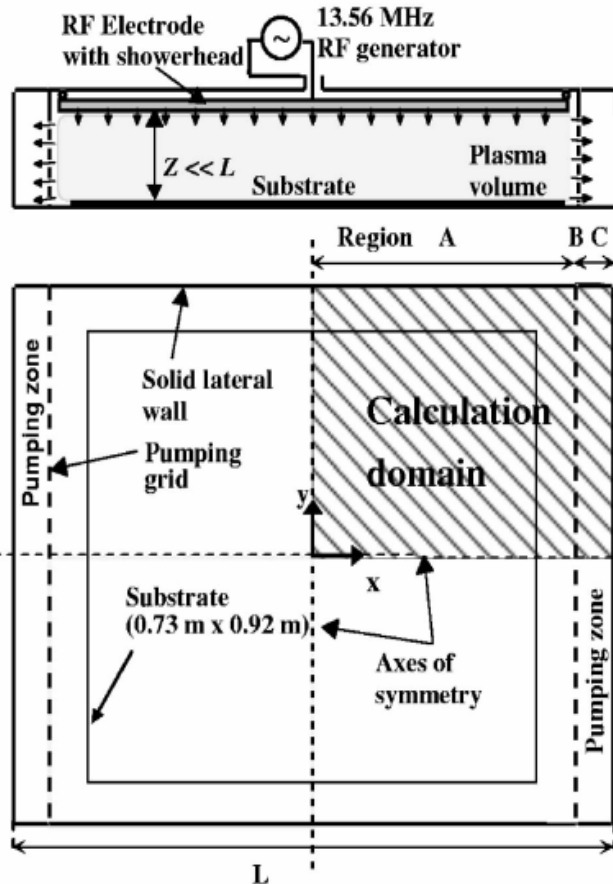
R. Sobbia *et al*, *J. Vac. Sci. Technol.* **A23**, 927 (2005)



3D, silicon nitride deposition.

Gas injection, standing wave and telegraph effect are calculated separately.

Number	Reaction	Rate constant (s ⁻¹ m ³)
Electron impact dissociations		
(R1)	$e^- + \text{NH}_3 \rightarrow \text{NH}_2 + \text{H} + e^-$	9.0×10^{-16}
(R2)	$e^- + \text{SiH}_4 \rightarrow \text{SiH}_2 + 2\text{H} + e^-$	1.9×10^{-16}
(R3)	$e^- + \text{SiH}_4 \rightarrow \text{SiH}_3 + \text{H} + e^-$	1.5×10^{-16}
(R4)	$e^- + \text{Si}_2\text{H}_6 \rightarrow \text{SiH}_4 + \text{SiH}_2 + e^-$	4.7×10^{-16}
Reactions with silane		
(R5)	$\text{SiH}_4 + \text{NH}_2 \rightarrow \text{SiH}_2 + \text{NH}_3 + \text{H}$	4.0×10^{-18}
(R6)	$\text{SiH}_4 + \text{NH}_2 \rightarrow \text{SiH}_2\text{NH}_2 + \text{H}_2$	1.0×10^{-17}
(R7)	$\text{SiH}_4 + \text{SiH}_2 \rightarrow \text{Si}_2\text{H}_6$	1.0×10^{-17}
Reactions between radical species		
(R8)	$\text{NH}_2 + \text{H}_2 \rightarrow \text{NH}_3 + \text{H}$	1.0×10^{-18}
(R9)	$\text{SiH}_2 + \text{H}_2 \rightarrow \text{SiH}_4$	2.0×10^{-19}
(R10)	$\text{SiH}_2 + \text{NH}_2 \rightarrow \text{SiH}_2\text{NH}_2$	7.8×10^{-17}
(R11)	$\text{SiH}_3 + \text{SiH}_3 \rightarrow \text{SiH}_4 + \text{SiH}_2$	1.5×10^{-16}
(R12)	$\text{SiH}_3 + \text{NH}_2 \rightarrow \text{SiH}_2 + \text{NH}_2$	2.1×10^{-17}
(R13)	$\text{SiH}_2\text{NH}_2 + \text{NH}_2 \rightarrow \text{Si}(\text{NH}_2)_2 + \text{H}_2$	9.8×10^{-17}
(R14)	$\text{Si}(\text{NH}_2)_2 + \text{NH}_2 \rightarrow \text{Si}(\text{NH}_2)_3$	1.0×10^{-16}
Reactions with disilane		
(R15)	$\text{Si}_2\text{H}_6 + \text{NH}_2 \rightarrow \text{Si}_2\text{H}_5 + \text{NH}_3$	1.7×10^{-17}
(R16)	$\text{Si}_2\text{H}_5 + \text{NH}_2 \rightarrow \text{SiH}_4 + \text{SiH}_2\text{NH}_2$	1.0×10^{-16}
(R17)	$\text{Si}_2\text{H}_6 + \text{H} \rightarrow \text{Si}_2\text{H}_5 + \text{H}_2$	6.5×10^{-18}
Surface (S) mechanisms		Sticking coefficient
(S1)	$\text{H} + \text{H} + \text{S} \rightarrow \text{H}_2$	1
(S2)	$\text{NH}_2 + \text{S} \rightarrow \text{N}(\text{S}) + \text{H}_2$	0.02
(S3)	$\text{SiH}_2 + \text{S} \rightarrow \text{Si}(\text{S}) + \text{H}_2$	0.8
(S4)	$\text{SiH}_2 + \text{NH}_2 + \text{S} \rightarrow \text{Si}-\text{N}(\text{S}) + 2\text{H}_2$	0.005
(S5)	$\text{SiH}_3 + \text{S} \rightarrow \text{Si}(\text{S}) + \text{H}_2 + \text{H}$	0.05
(S6)	$\text{Si}_2\text{H}_5 + \text{S} \rightarrow \text{Si}(\text{S}) + 2\text{H}_2 + \text{H}$	0.05
(S7)	$\text{Si}(\text{NH}_2)_2 + \text{S} \rightarrow \text{N}-\text{Si}-\text{N}(\text{S}) + 2\text{H}_2$	0.02
(S8)	$\text{Si}(\text{NH}_2)_3 + \text{S} \rightarrow \text{N}-\text{Si}-\text{N}(\text{S}) + \text{NH}_3 + \text{H}_2 + \text{H}$	0.003



Navier-Stokes $\nabla \cdot (\rho \mathbf{v} \mathbf{v}) = -\nabla p + \nabla \cdot (\mu \nabla \mathbf{v}),$

Species continuity $\nabla \cdot (\rho \mathbf{v} Y_i) = -\nabla \cdot \mathbf{J}_i + R_i + S_i,$

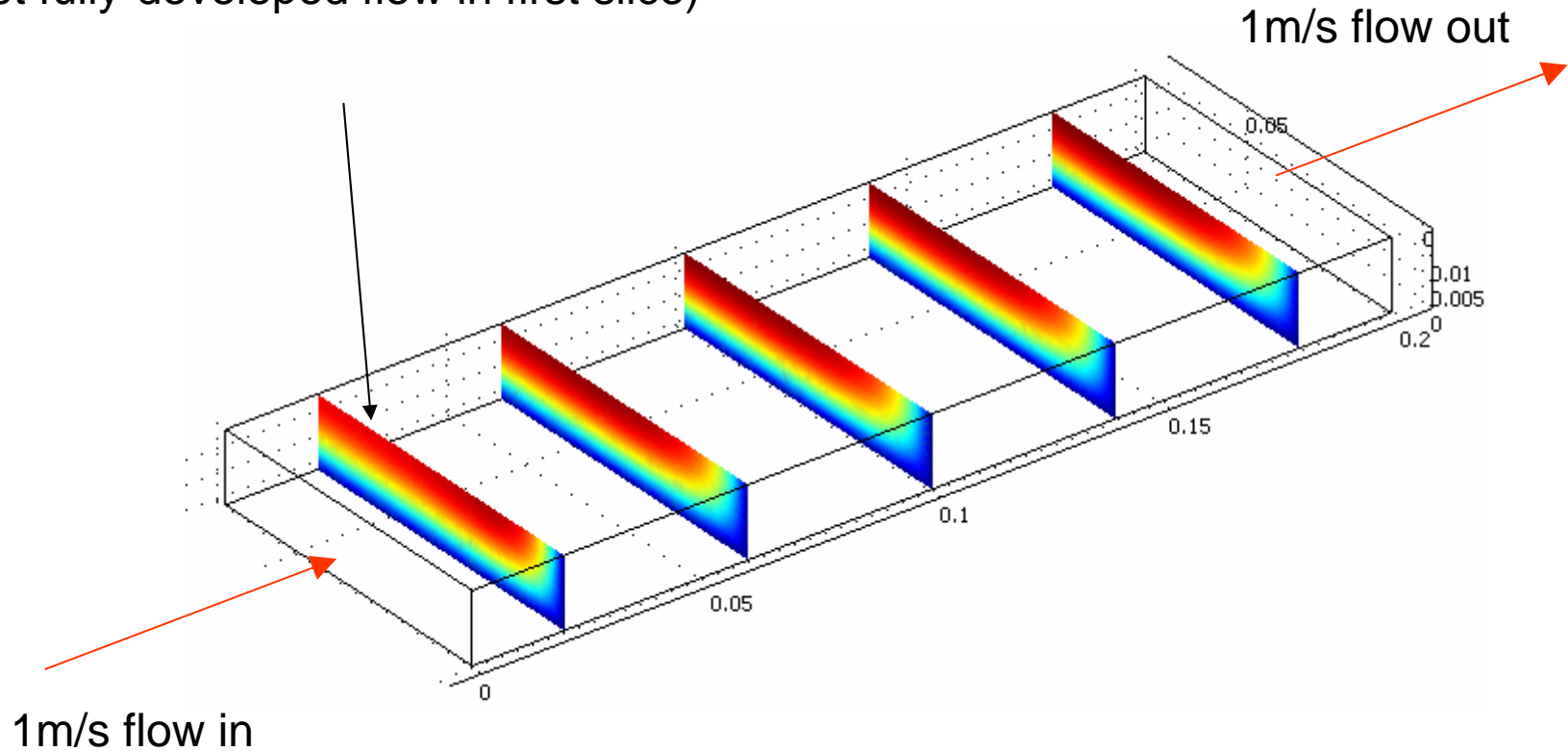
Diffusive mass flux $\mathbf{J}_i = \mathbf{J}_i^C = -\rho D_i^{\text{eff}} \nabla Y_i + M Y_i D_i^{\text{eff}} \sum_{j=1, j \neq i}^N \frac{\mathbf{J}_j^C}{M_j D_{ij}}$

Comsol for Navier-Stokes numerical simulations:

for example, channel flow

Half-height, edge region

(not fully-developed flow in first slice)

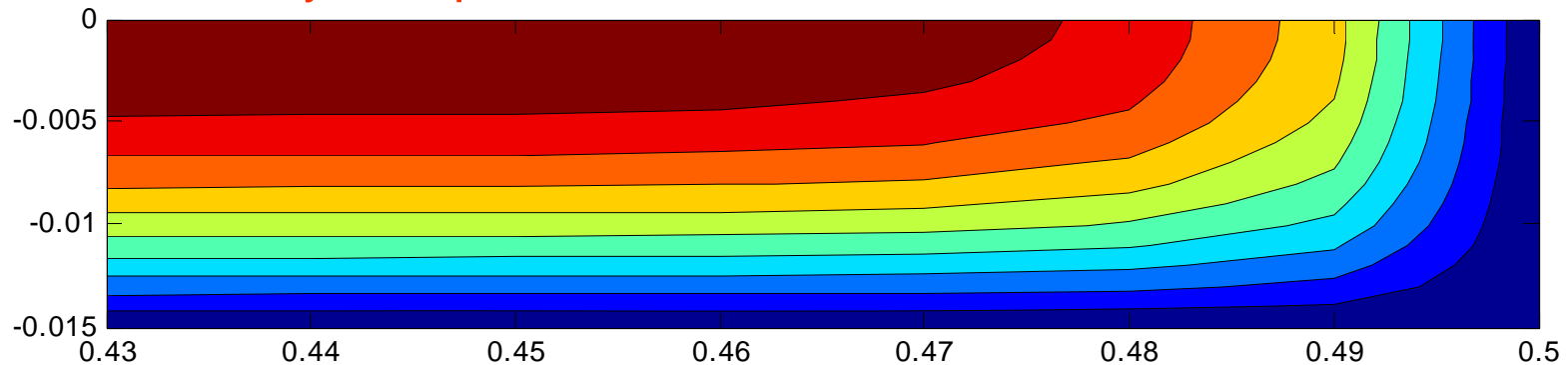


Compare analytical expression (using Matlab)
with numerical simulation above (Comsol, Navier-Stokes)

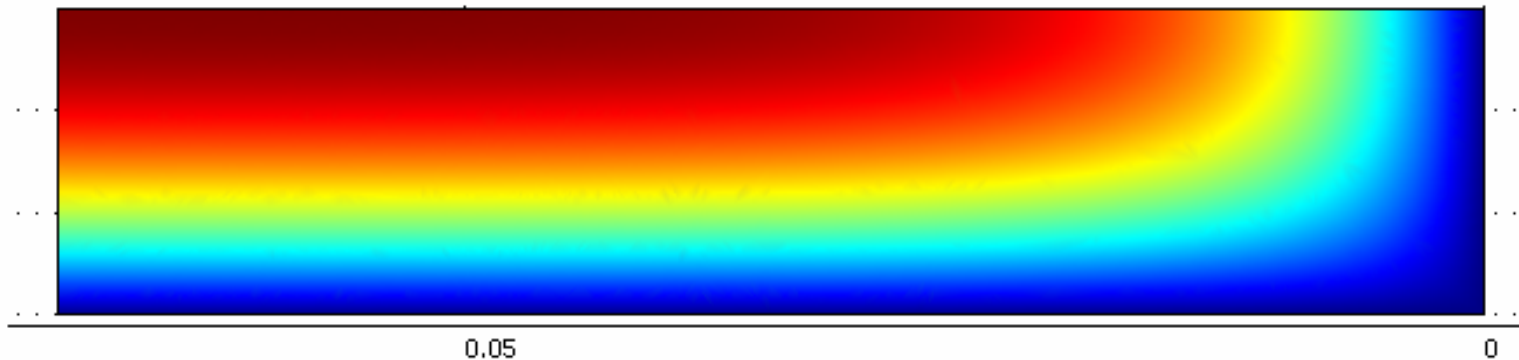
$$u(y, z) = \frac{16a^2}{\mu\pi^3} \left(-\frac{dp}{dx} \right) \sum_{i=1,3,5,\dots}^{\infty} \frac{(-1)^{(i-1)/2}}{i^3} \left[1 - \frac{\cosh(i\pi z/2a)}{\cosh(i\pi b/2a)} \right] \cos\left(\frac{i\pi y}{2a}\right)$$

in F. M White "Viscous Flow" McGraw-Hill, NY

analytic expression



numerical simulation



CONCLUSION: Analytic solutions still have a wide application, even in a numerical world!